
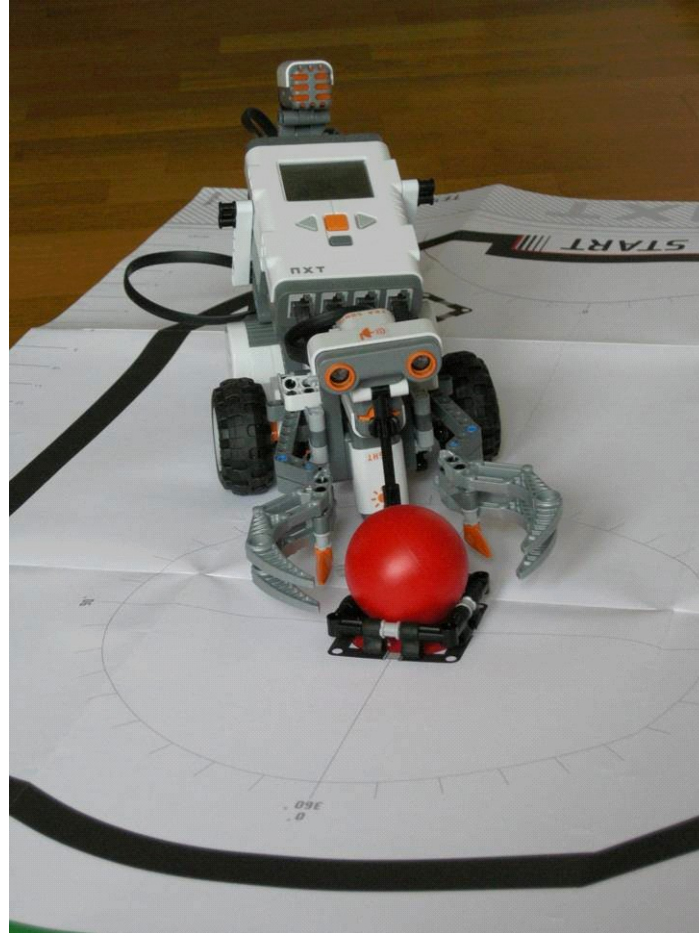


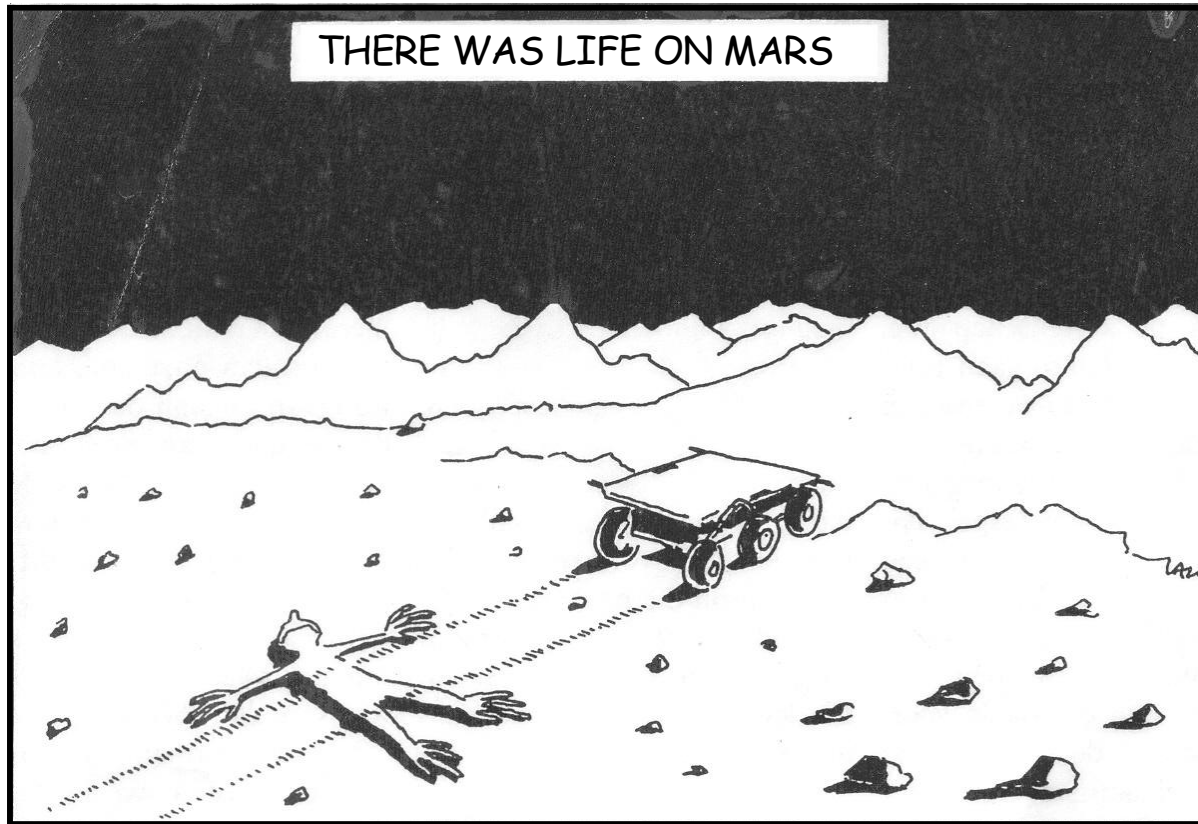
Extending Vector Network Analyzers

- 
- *Characterization of diodes, transistors and amplifiers* -
 - *in frequency and time domain* -

A little story



A little story



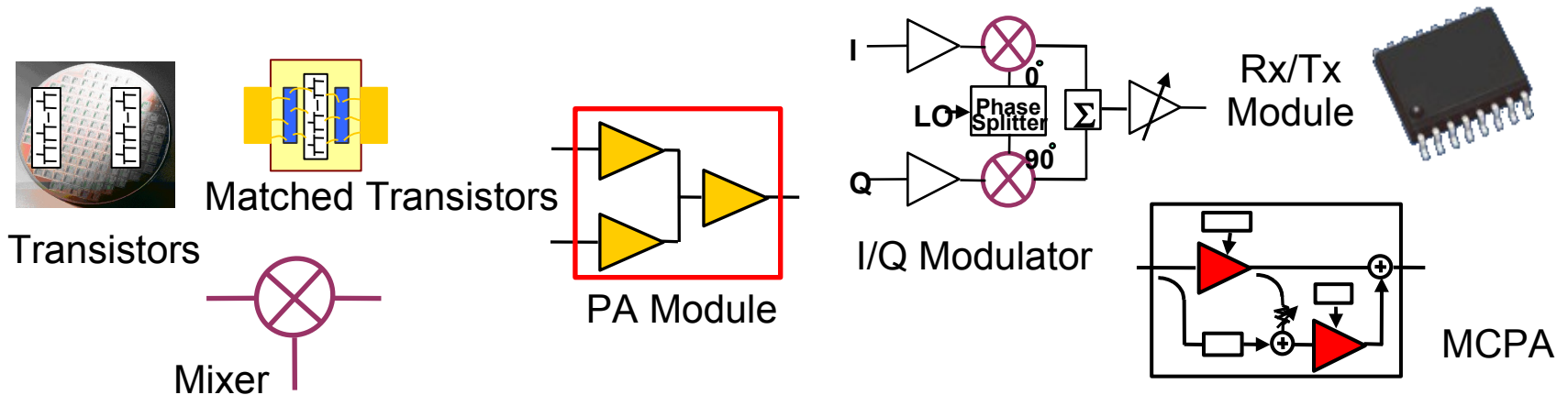
Agenda

- Why extending vector network analyzers?
- Large-Signal Network Analysis
- Commercial Solutions
- Theory of Operation of VNAPlus
- Capabilities of VNAPlus
- Applications
 - Breakdown effects
 - Model verification in ADS
 - In-circuit Probing
- VNAPlus and “Sensing Tuner”: a new frontier
- Conclusions

Design Challenge

“Customers are demanding more capabilities/performance from their devices at lower cost”

- Designers are looking for better and faster methods of characterizing their components

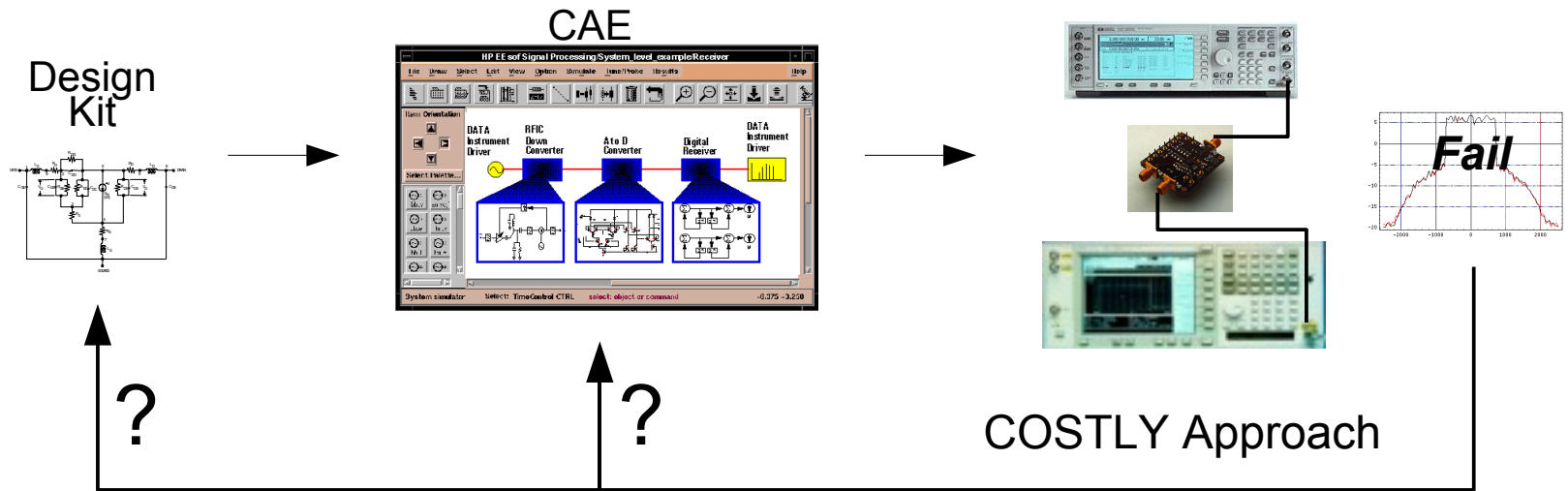


Demands translate to greater design complexities

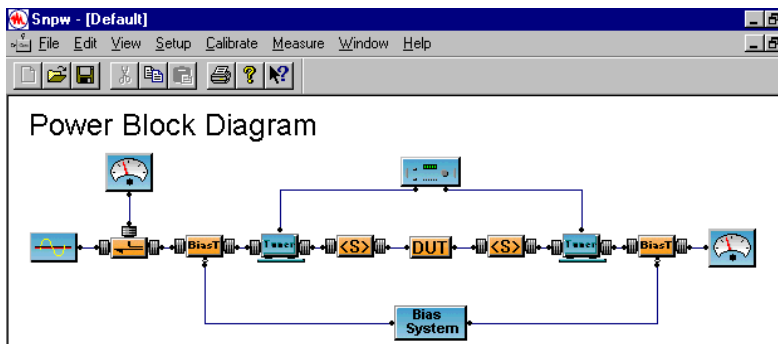
- More complex modulation schemes
- Higher power efficiency requirements
- Improved linearity

Model Verification Techniques

- Design, manufacture and test under realistic conditions



- Load-Pull characterization at device level

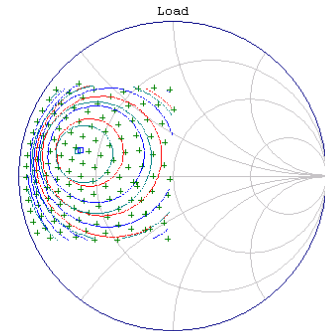


Power Only

```

Fixed Load Pull
Freq = 14.0000 GHz
TSource: 0.0014< 127.23

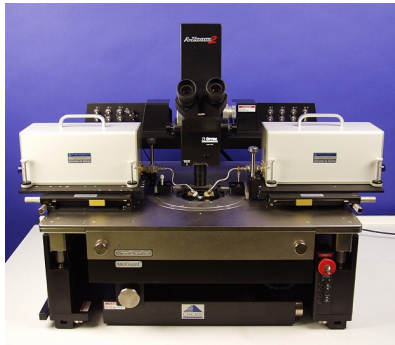
Pout max = 4.98 dBm
at 0.6125< 164.34
5 contours, 0.50 dBm step
(2.50 to 4.50 dBm)
Gt max = 4.98 dB
at 0.6125< 164.34
5 contours, 1.00 dB step
(0.00 to 4.00 dB)
Eff max = 8.88 %
at 0.6285< 165.71
5 contours, 2.00 % step
(0.00 to 8.00 %)
Specs: OFF
    
```



“What happens at the transistor?”

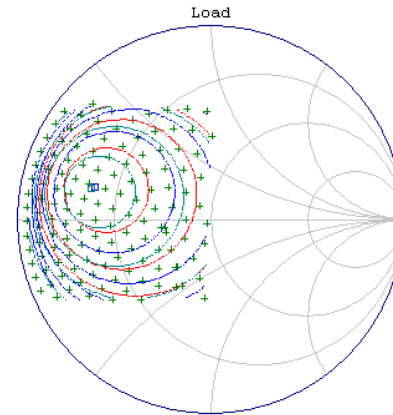
Direct design techniques

- Source- and load-pull- characterization
 - Absence of good models
 - Difficult to extract good model parameters
 - Mainly power information



```
Fixed Load Pull
Freq = 14.0000 GHz
PSource: 0.0014< 127.23

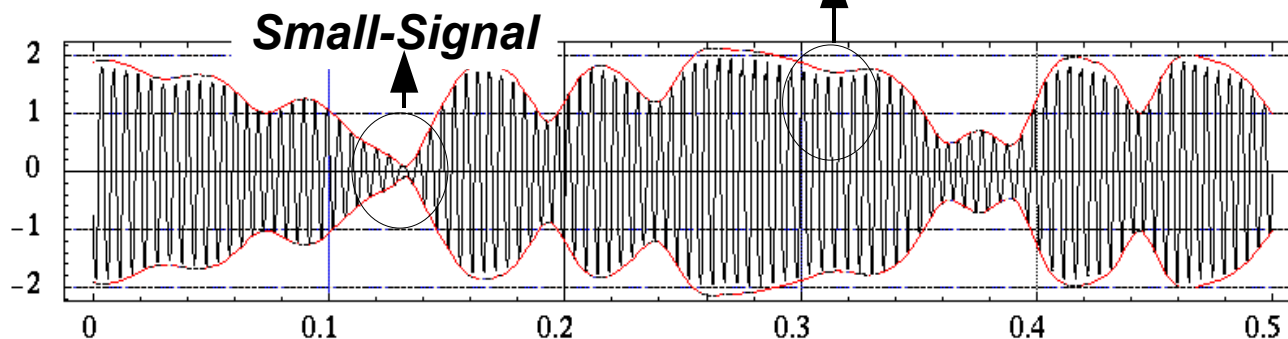
Pout      max = 4.98 dBm
          at 0.6125< 164.34
          5 contours, 0.50 dBm step
          (2.50 to 4.50 dBm)
Gt        max = 4.98 dB
          at 0.6125< 164.34
          5 contours, 1.00 dB step
          (0.00 to 4.00 dB)
Eff       max = 8.88 %
          at 0.6285< 165.71
          5 contours, 2.00 % step
          (0.00 to 8.00 %)
Specs: OFF
```



“For each input power”

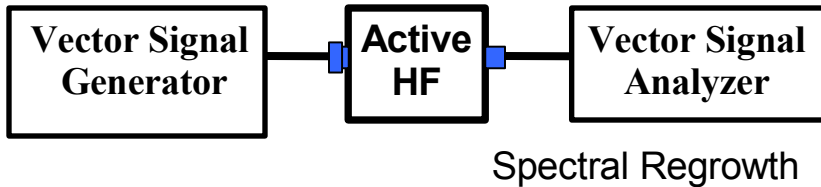
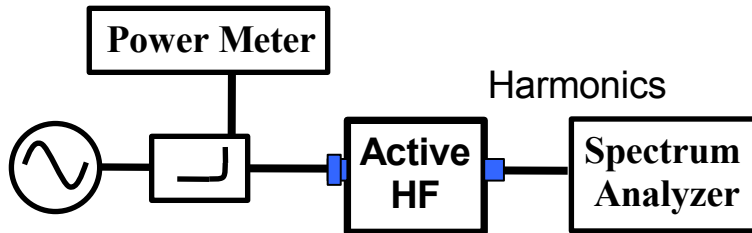
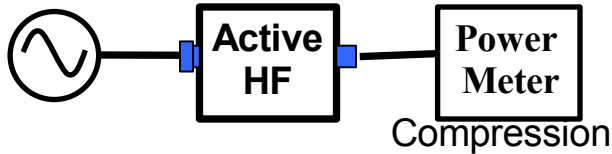
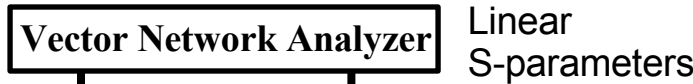
Label:
FET

- But: What under modulation stimulus? **Large-Signal**

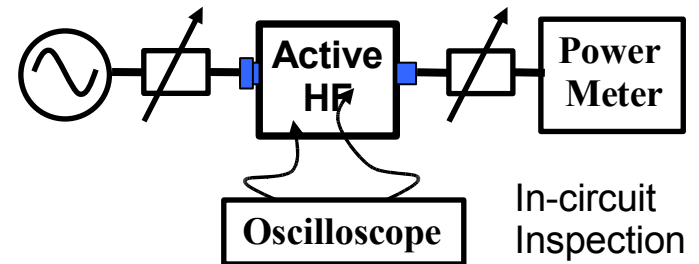
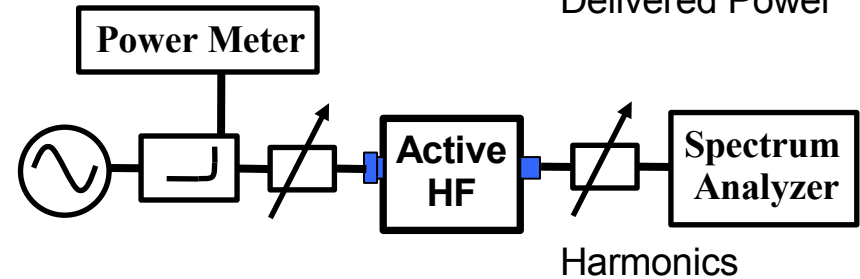
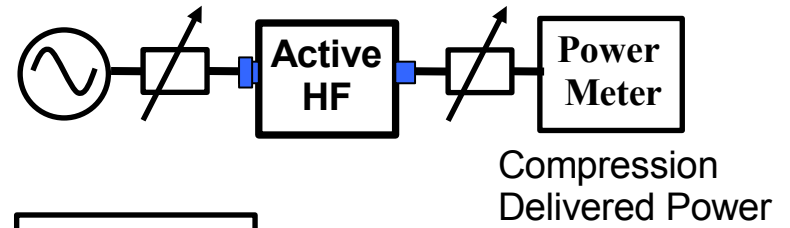


Component Characterization

50 Ohm Termination



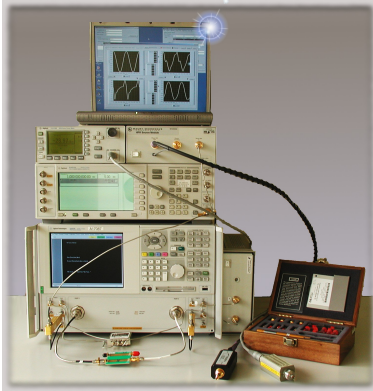
Source and Load Tuning



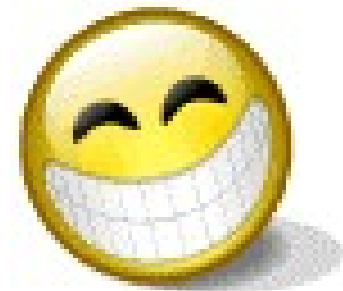
**Different Setups
for different aspects
without systematic approach**

**How to help the circuit designers,
needing good models?**

Extending a vector network analyzer with VNAPlus



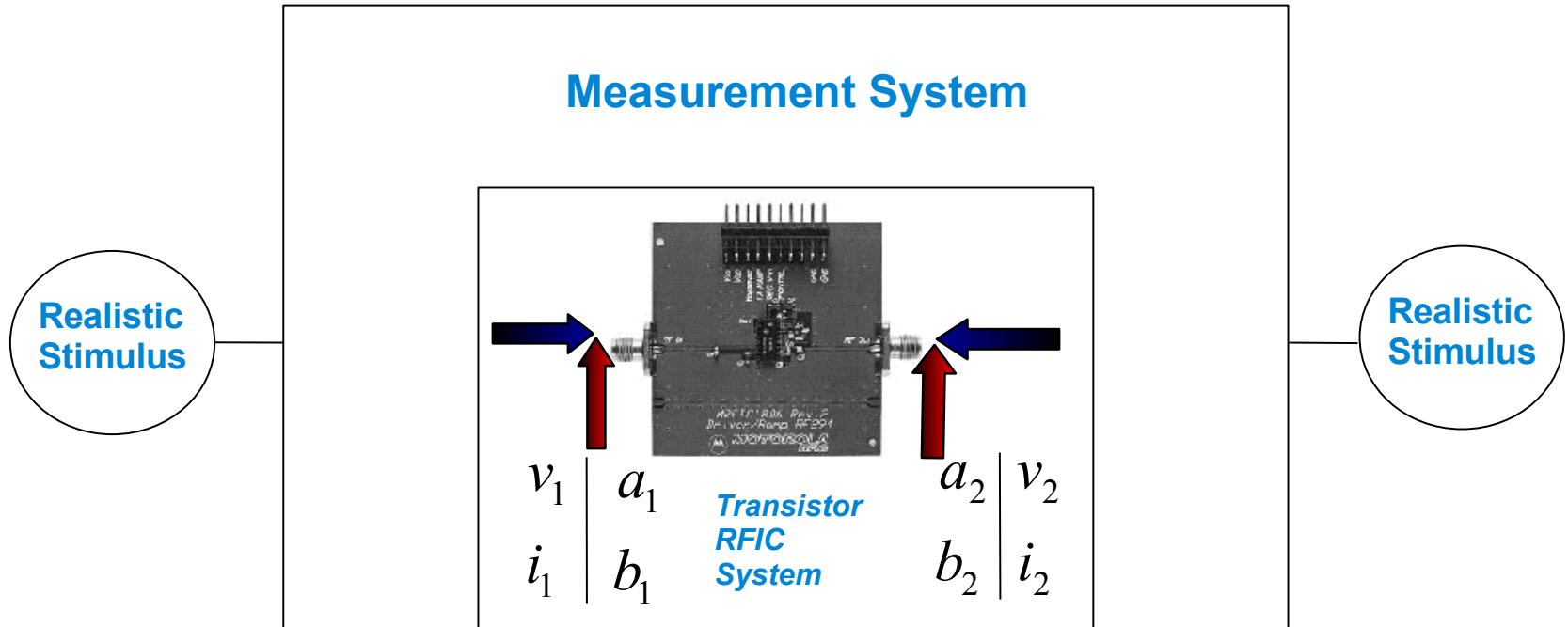
Measuring directly
accurately and completely
the true nonlinear behavior
under realistic conditions
at the device level



Based on Large-Signal Network Analyzer Technology

A Large-Signal Network Analyzer

“Complete insight in large-signal behavior”



• Representation Domain

- Frequency (f)
- Time (t)
- Freq - time (envelope)

• Physical Quantity Sets

- Travelling Waves (A, B)
- Voltage/Current (V, I)

• Analysis

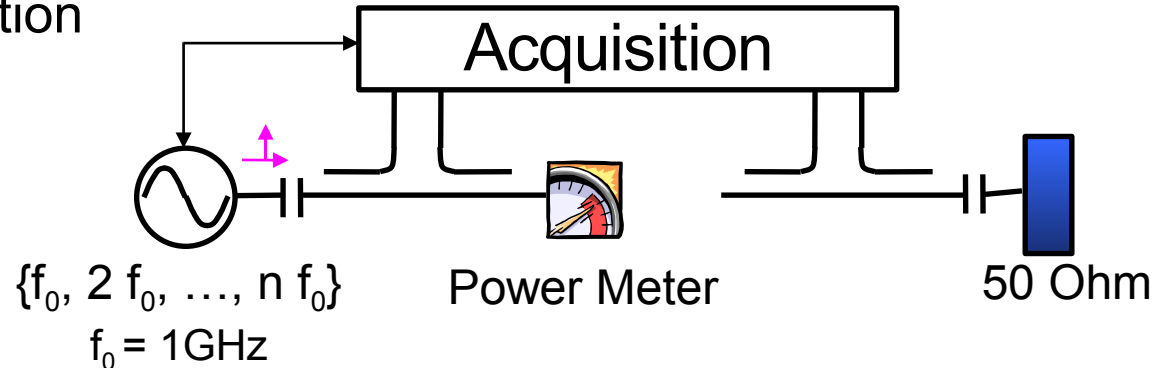
$$g(v_1, v_2, i_1, i_2, t | f) = 0$$

$$h(v_1, v_2, i_1, i_2, t | f) = 0$$

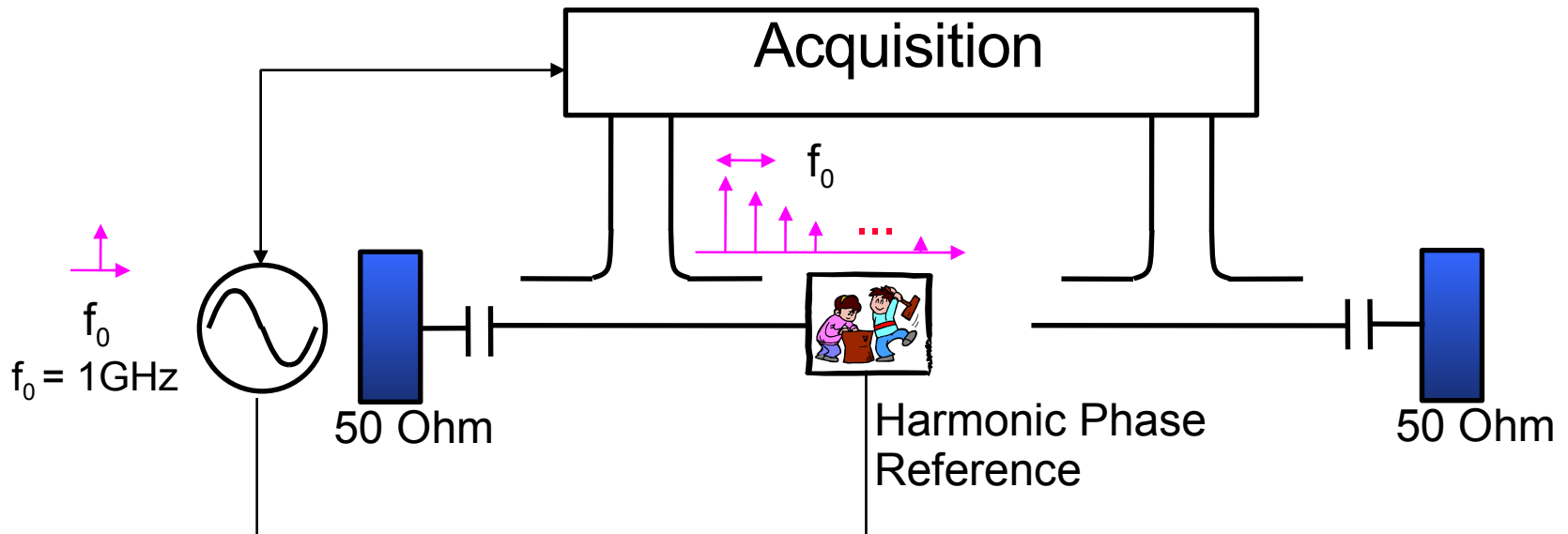
←—————→
Characterization

Calibration technique

- Relative calibration, similar to VNA calibration
 - SOLT, TRL, LRRM ...
- Absolute calibration
 - Power



- Phase

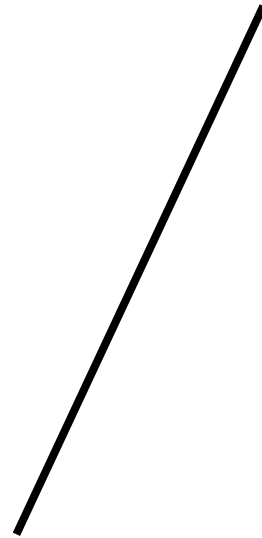
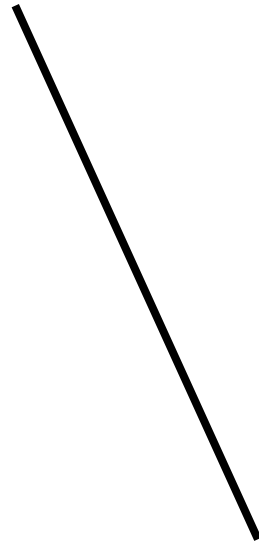


Measurement Traceability

Relative Cal

Phase Cal

Power Cal



Agilent
Nose-to-Nose
Standard (*)

EOS



(NIST)

(demonstrated
already with NIST)

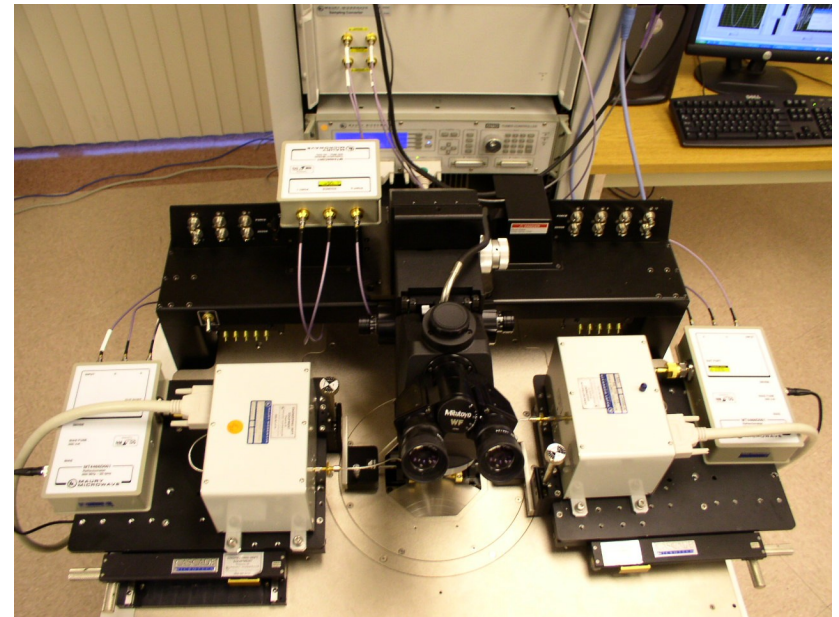
National Standards

(*) Licensed to Maury and NMDG

MT4463A - 20 GHz



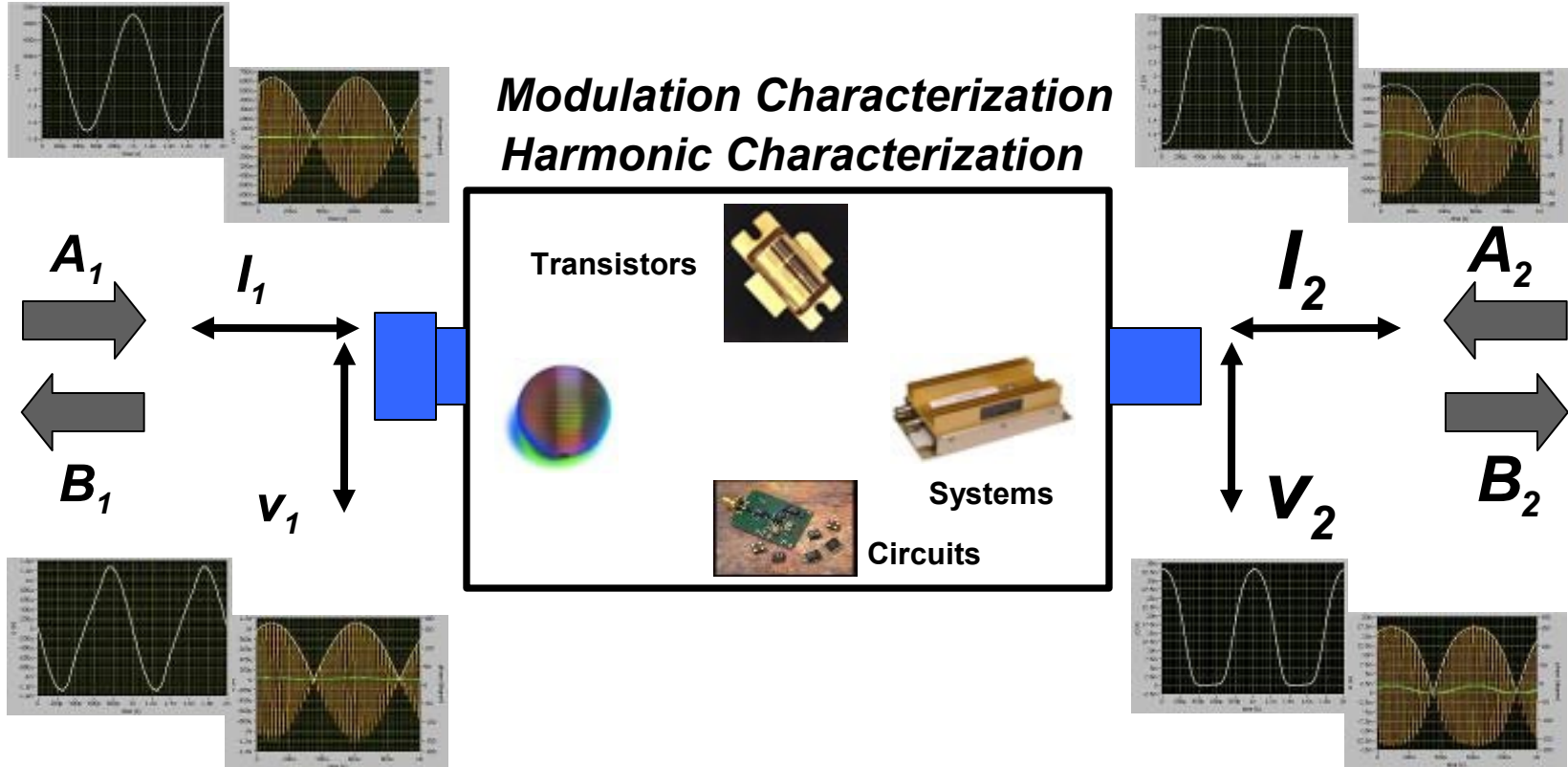
MT4463B - 50 GHz



MT4463 measures...

Accurately
Completely
In a traceable way

Modulation Characterization Harmonic Characterization



In following domains

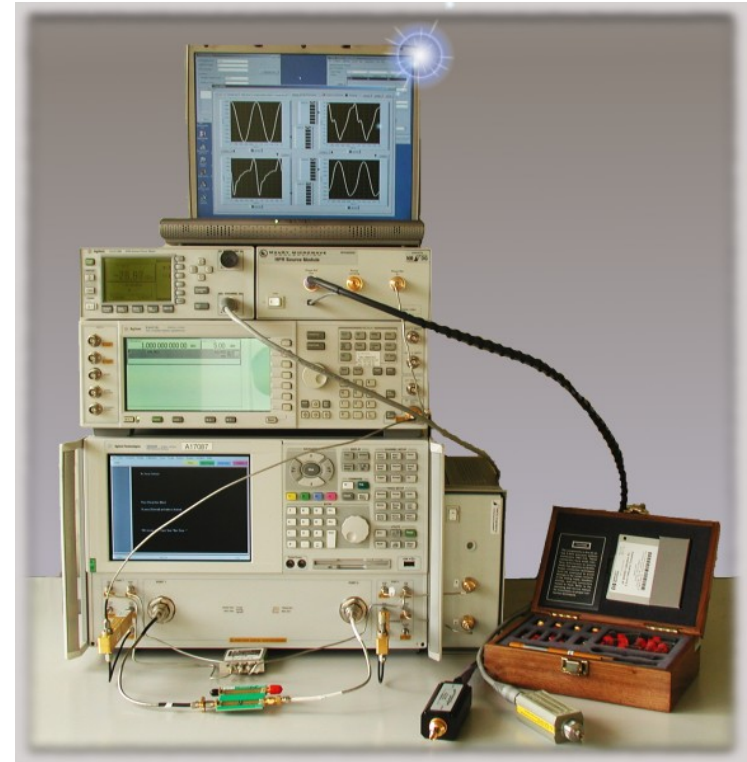
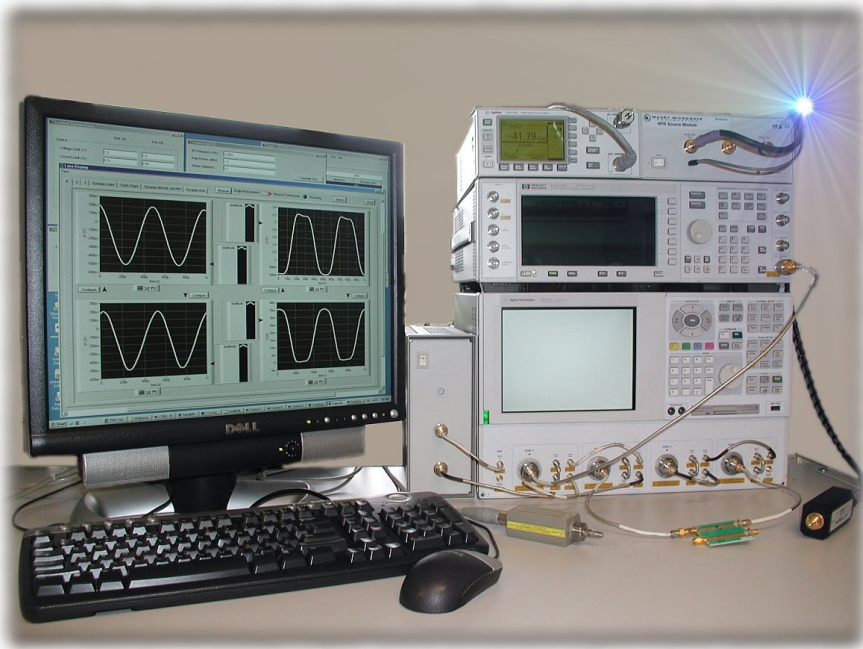
- Frequency domain
- Frequency - time domain
- Time domain

*Compatible with
Simulation Tools*

Under realistic conditions

- Continuous wave
- Periodic Modulation
- Source and Load Tuning

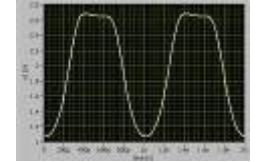
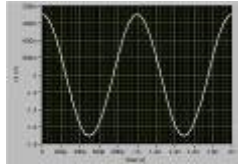
VNAPlus



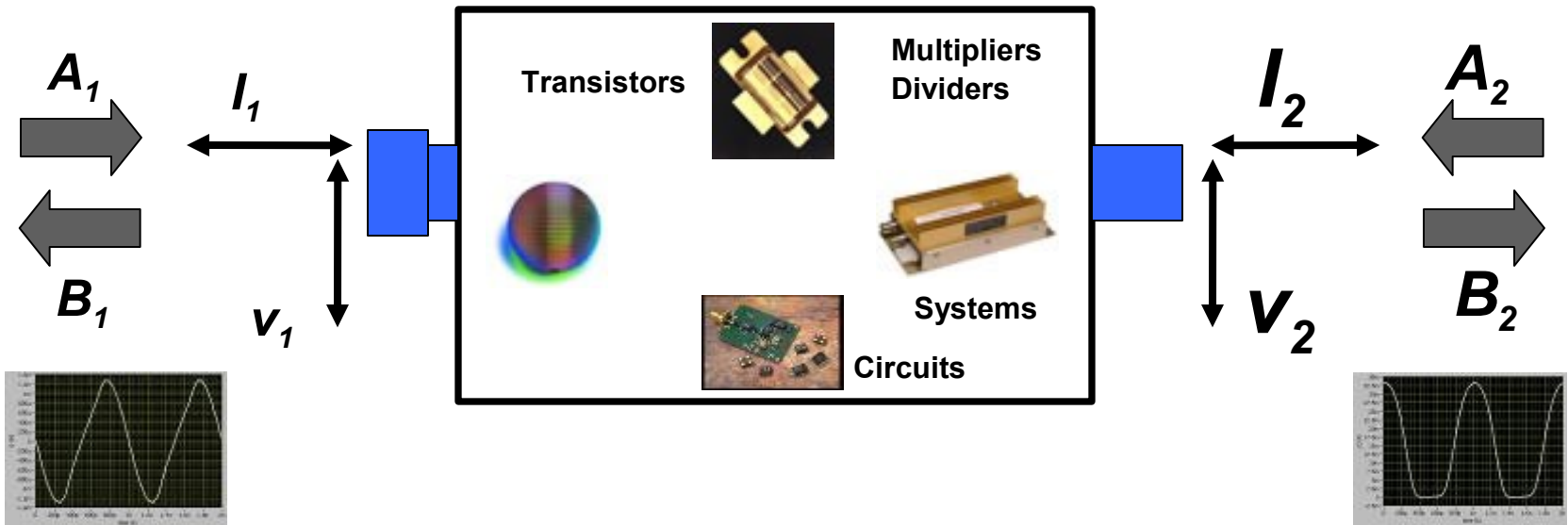
Requires: Agilent N5230A or Agilent E836X Opt 080 + config. Test set
Synchronizer, enabling nonlinear time domain characterization
External synthesizer with frequency range, covering the application needs
3.5 mm Calibration kit
Power meter, for power calibration
Harmonic Phase Reference, for phase calibration

VNAPlus measures...

Accurately
In a traceable way



Harmonic Characterization



In following domains

Frequency domain

Time domain

Under realistic conditions

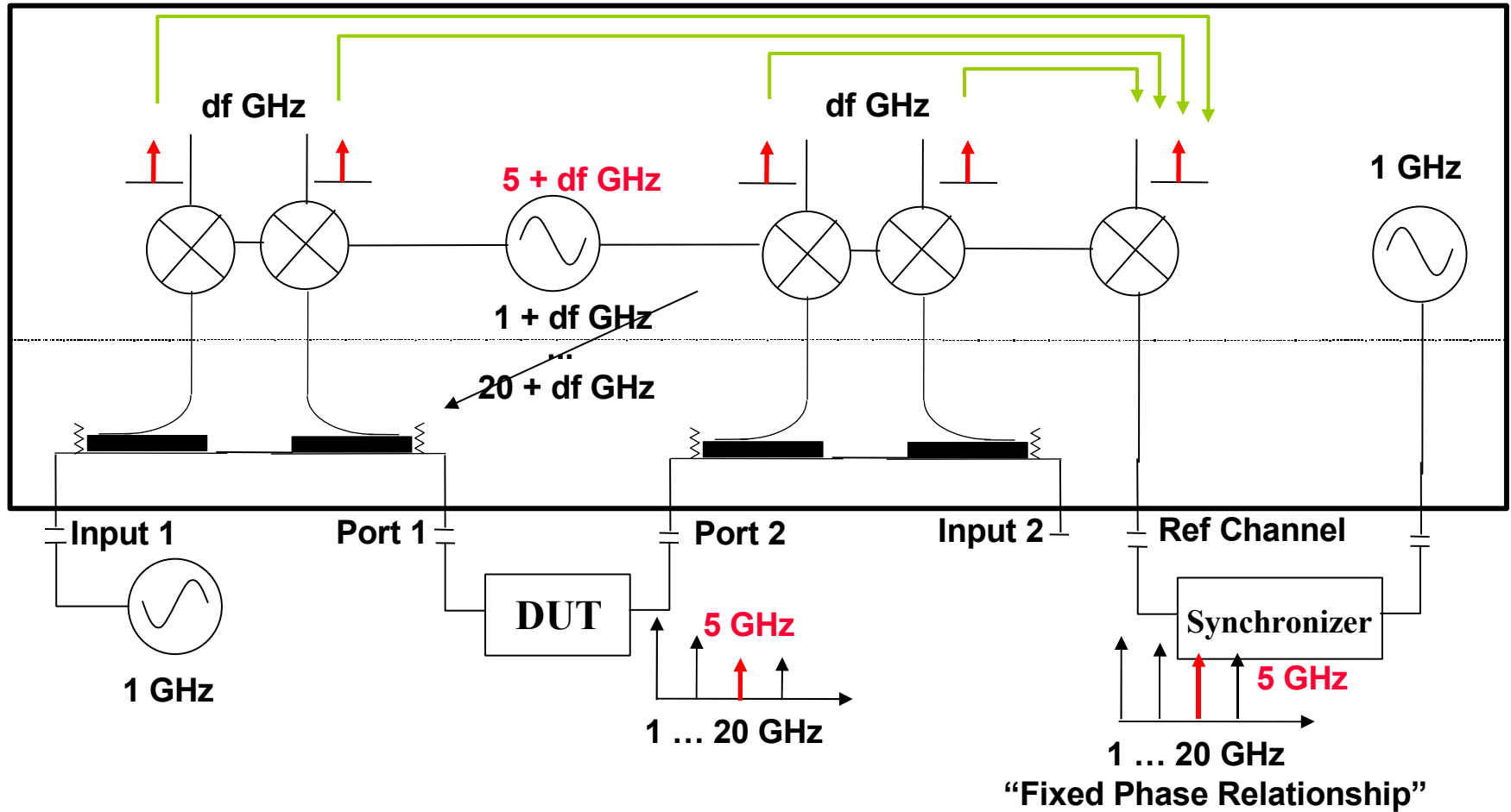
Continuous wave

**Non 50 Ohm environment
[Source and Load Tuning]**

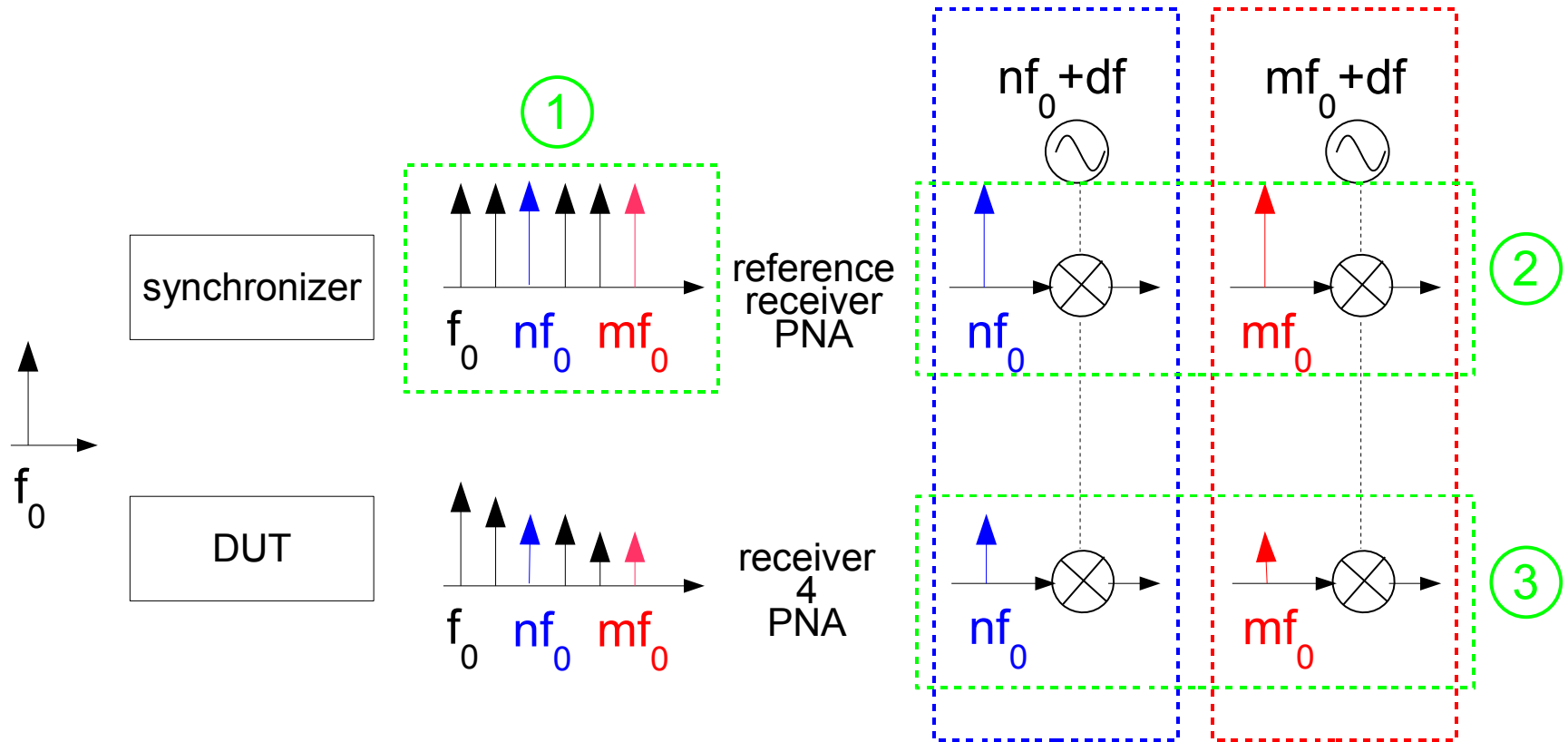
*Compatible with
Simulation Tools*

VNAPlus: Theory of Operation

Network Analyzer



VNAPlus: Theory of Operation

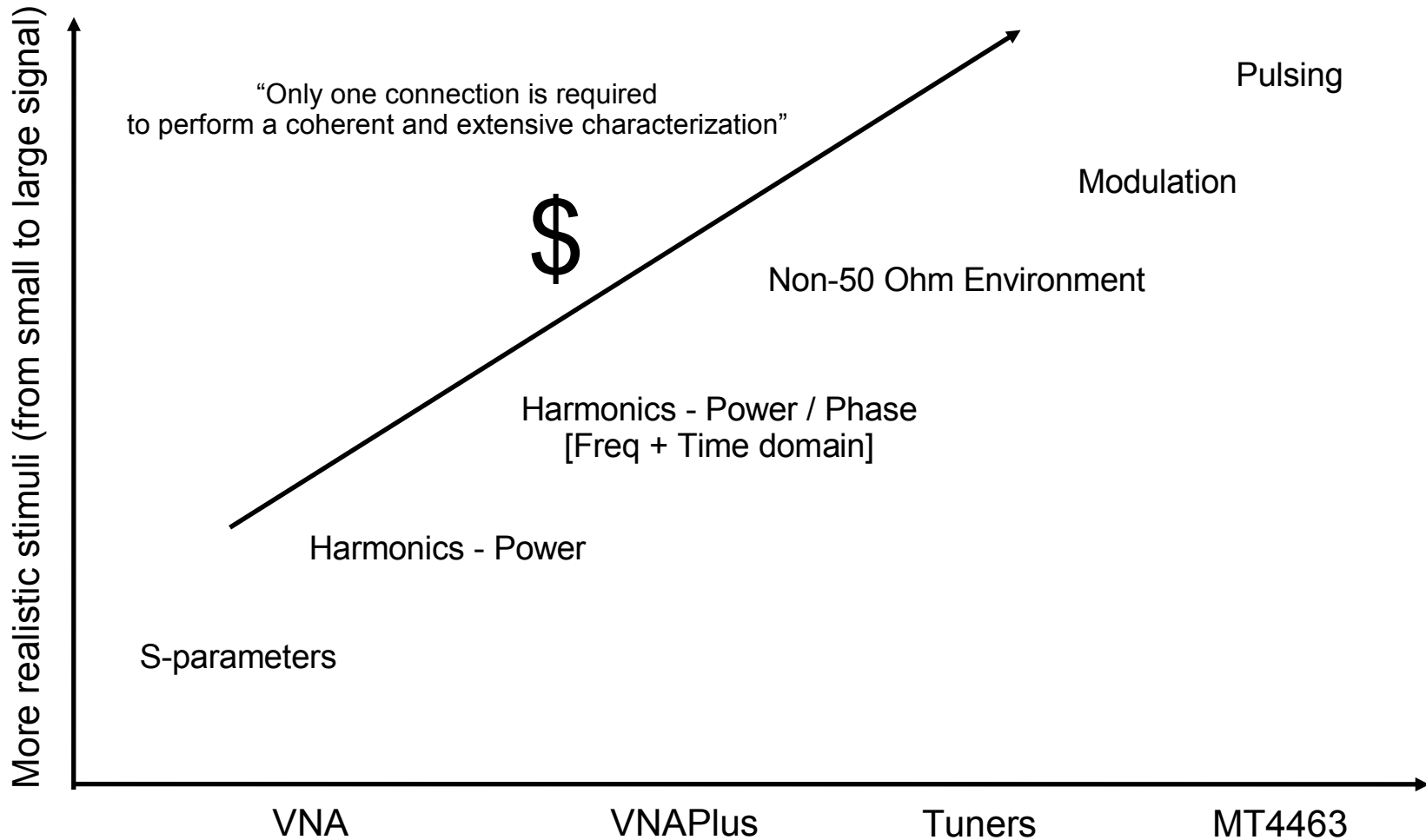


phase consistency between harmonics in

① ② ③

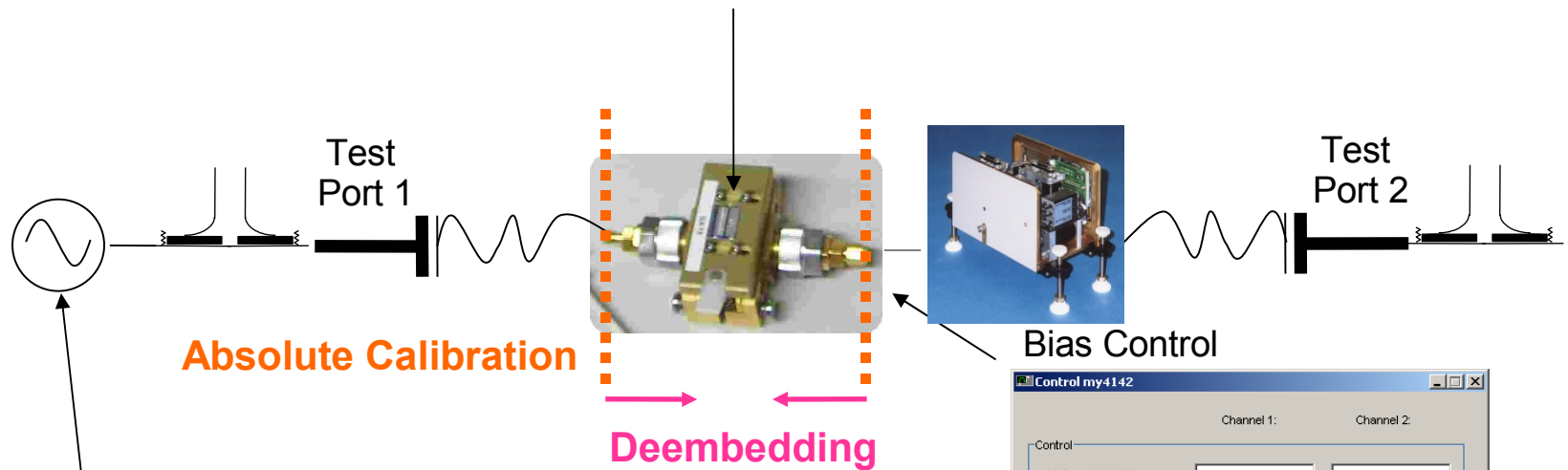
phase consistency between receivers
by simultaneous measurement
one frequency at the time

All-in-one with one calibration

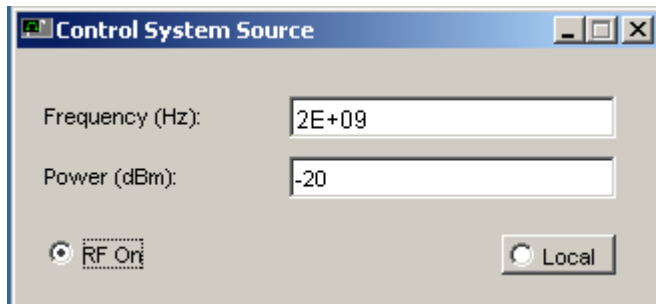


From small - signal to large - signal with ONE connection

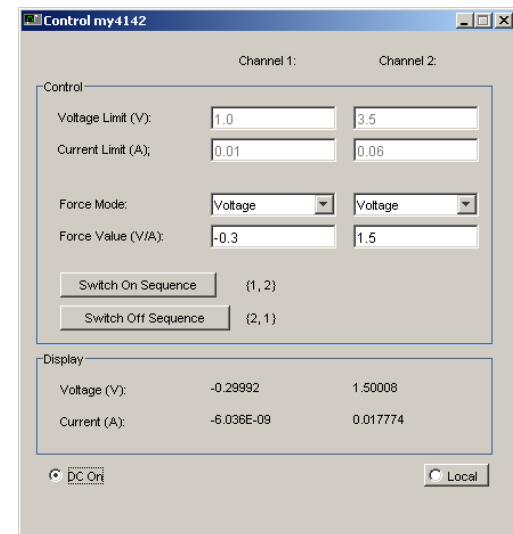
Commercial available FET in fixture



Synthesizer Control

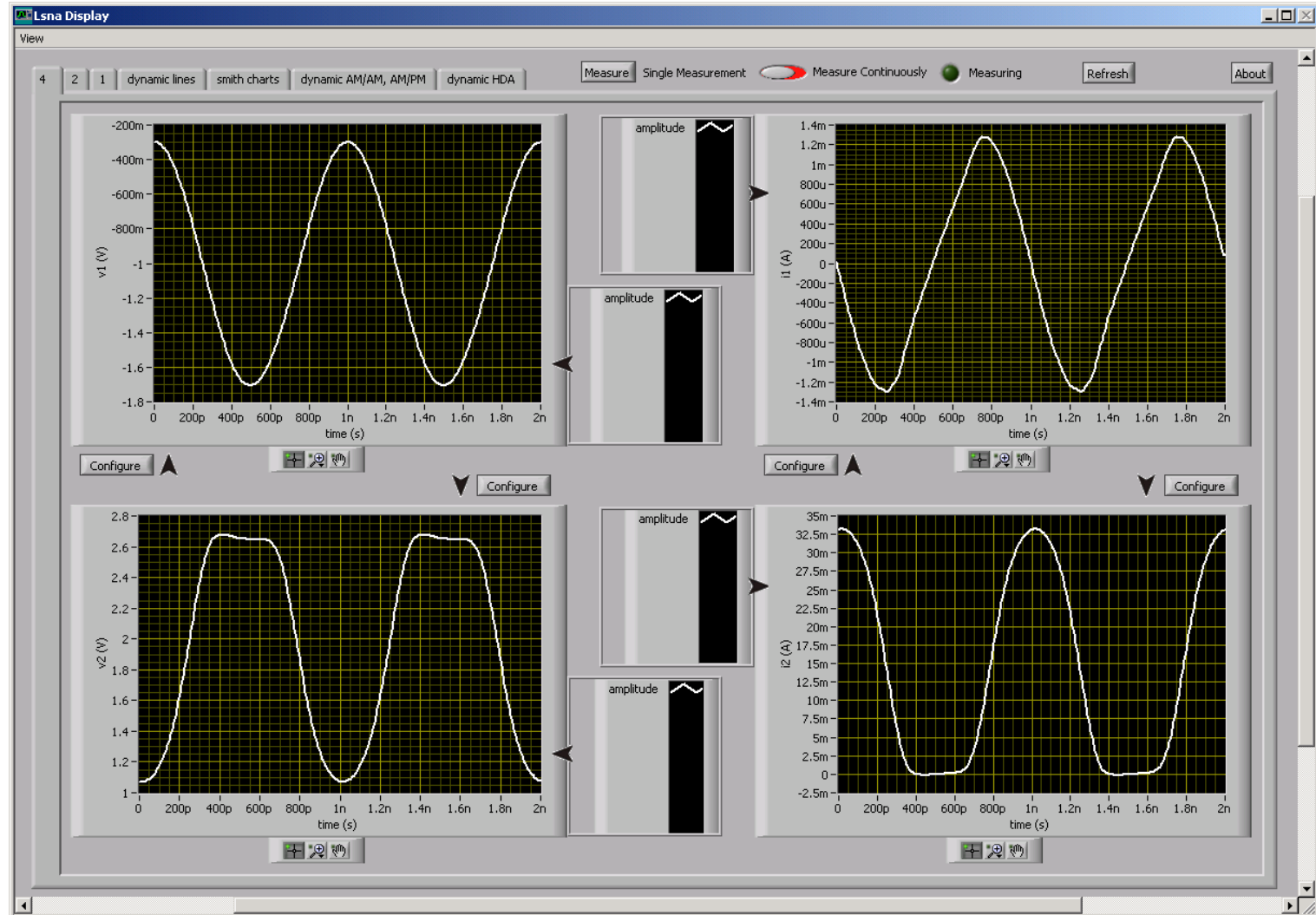


Bias Control



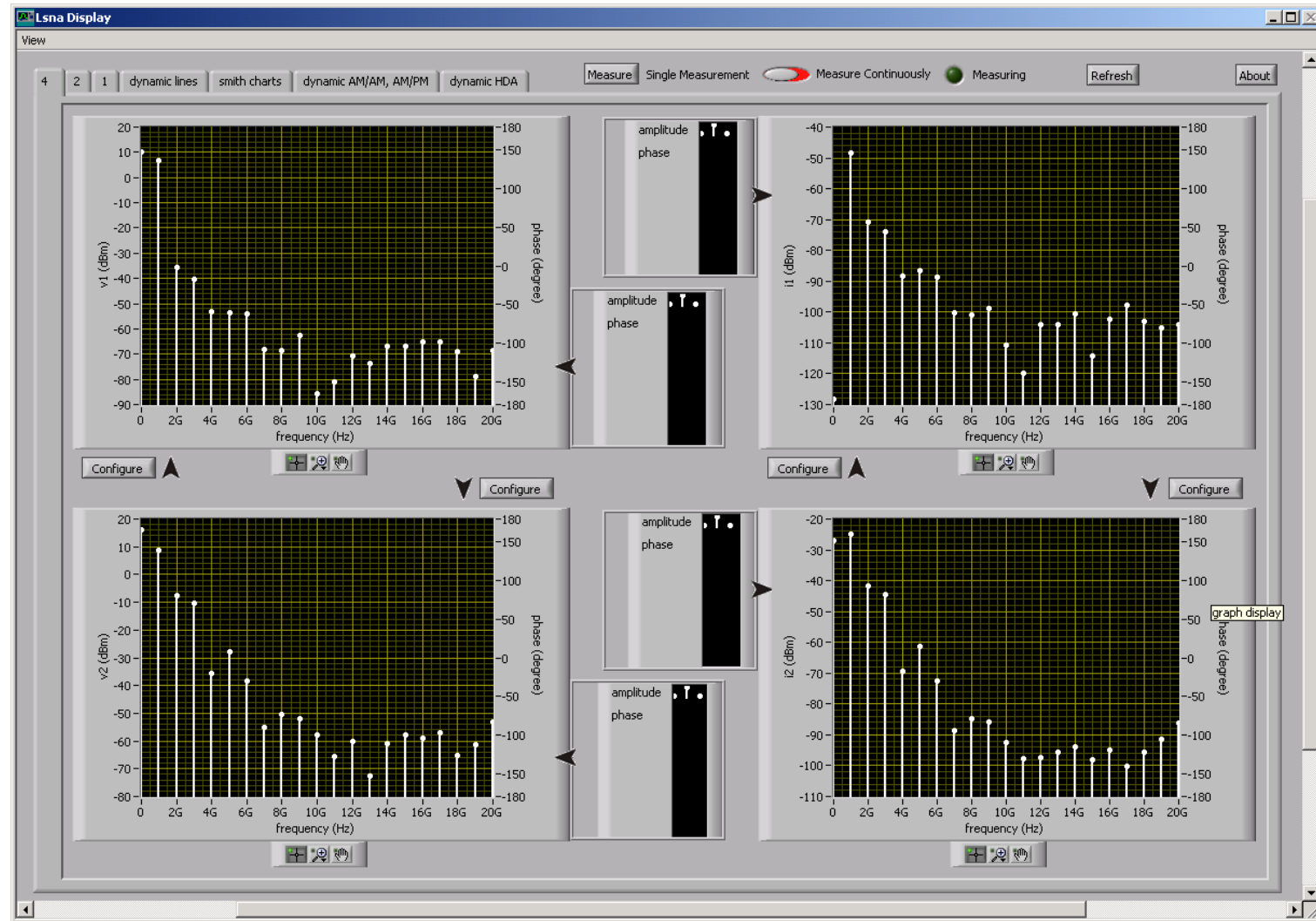
$$V_{gs} = -0.3 \text{ V } V_{ds} = 1.5 \text{ V}$$

Large-Signal Measurements - CW - Voltage/Current



Time domain

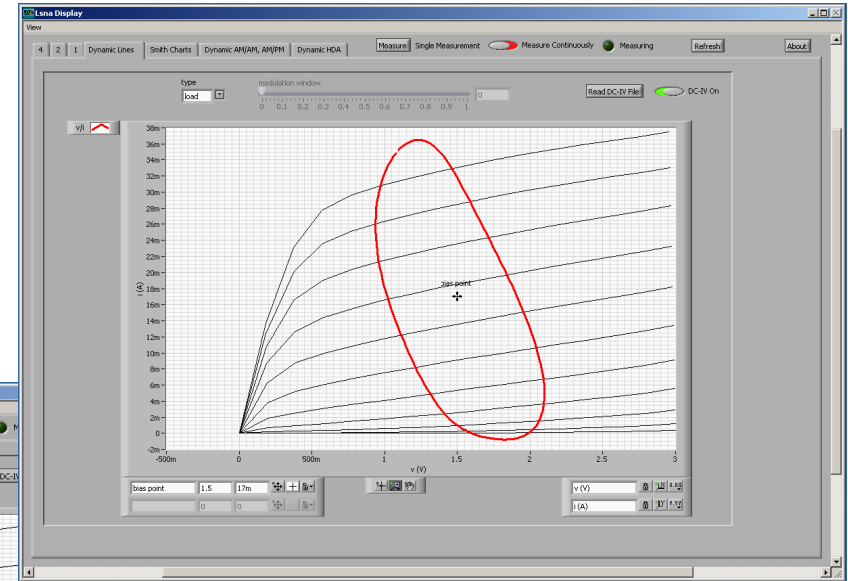
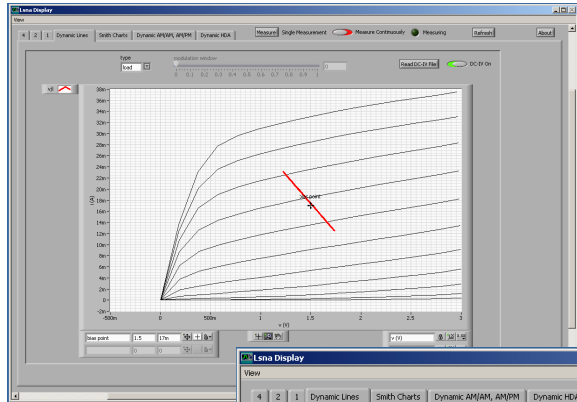
Large-Signal Measurements - CW - Voltage/Current



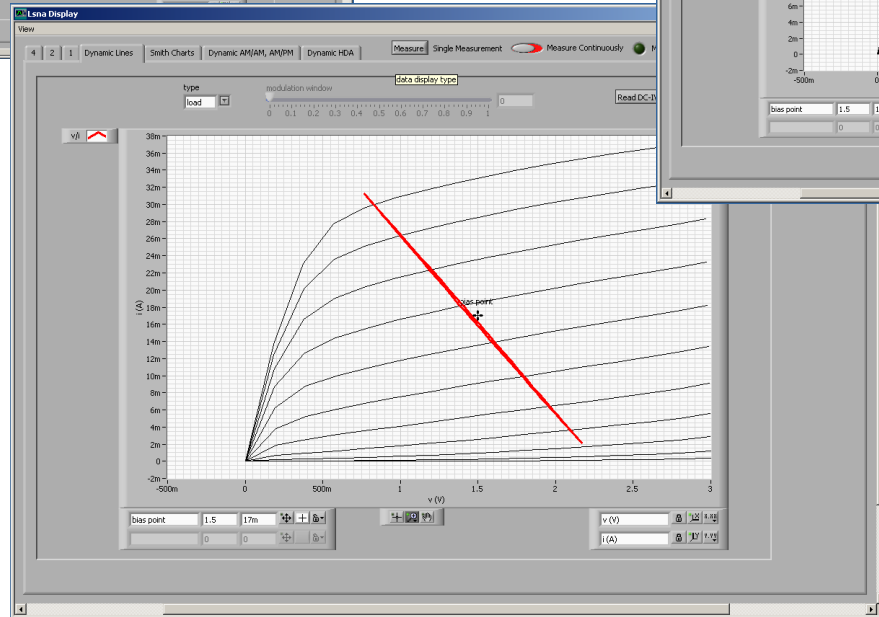
Frequency domain

DC-IV curve and load line

Small-signal - 50 Ohm Termination

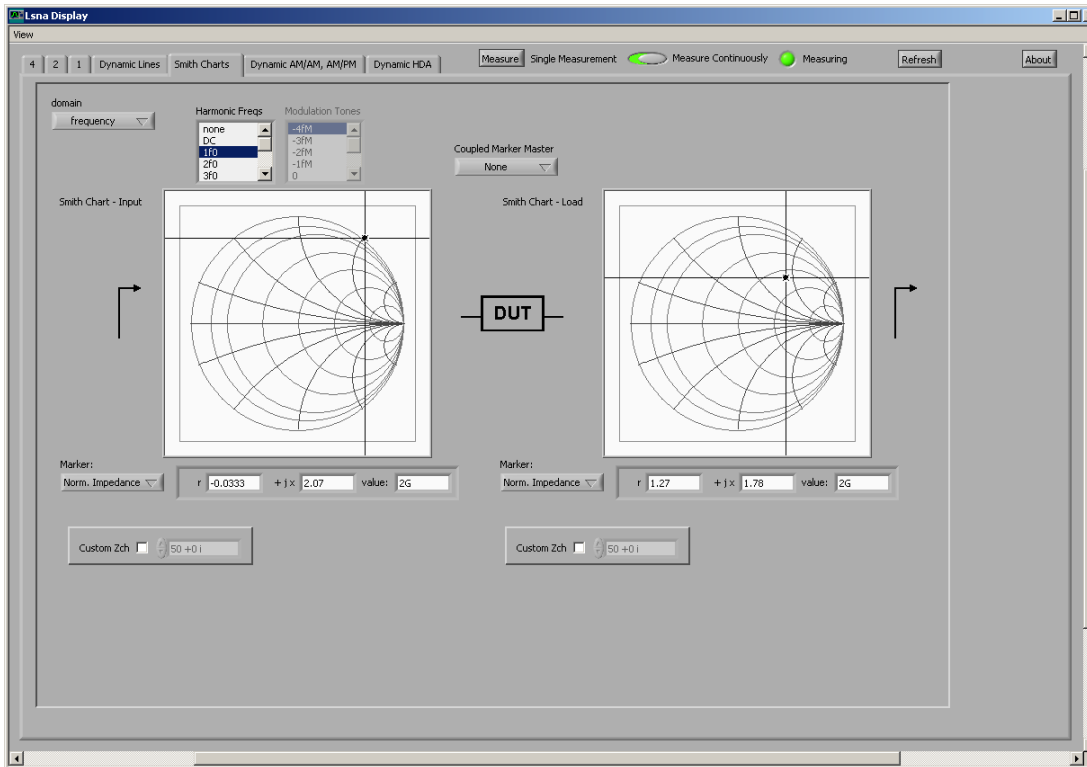


Large-signal - non-50 Ohm Termination



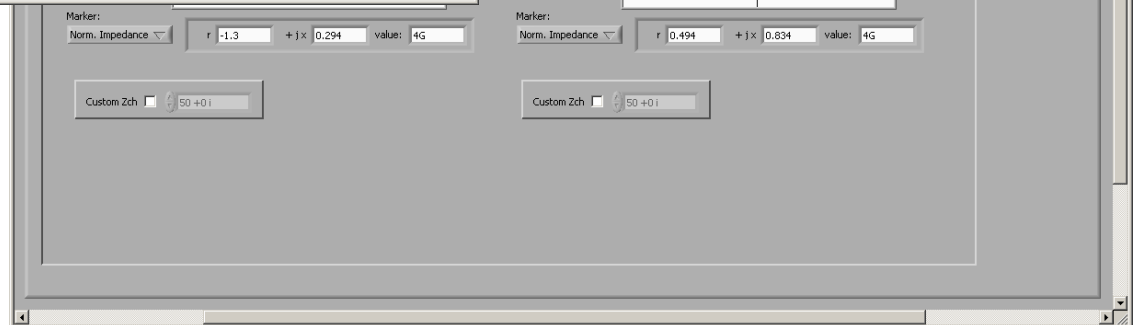
Large-signal - 50 Ohm Termination

Input and Load impedance under CW

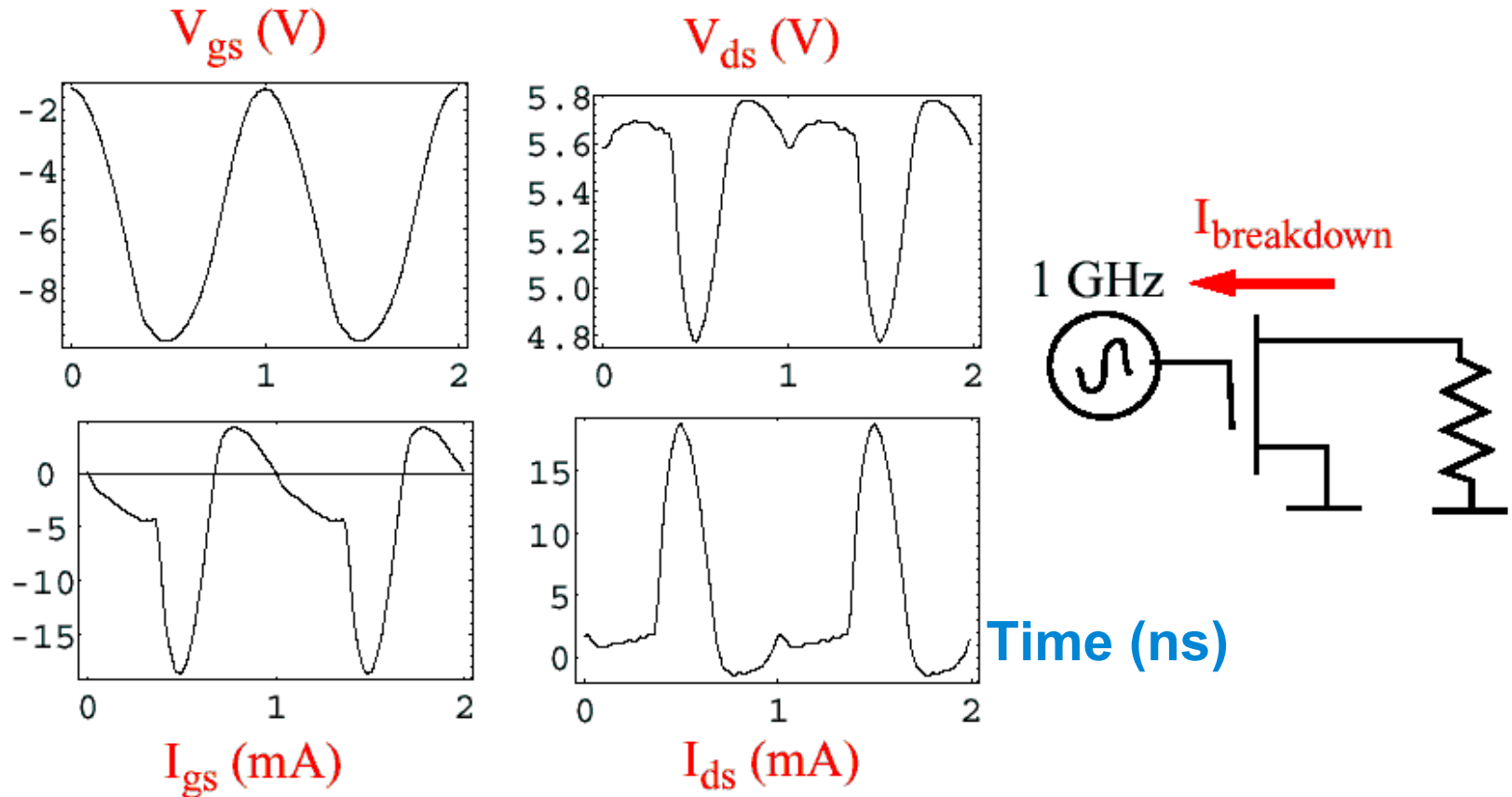


Impedance at fundamental non-50 Ohm Termination

Impedance at 2nd harmonic non-50 Ohm Termination



Application #1: Gate-Drain Breakdown Current

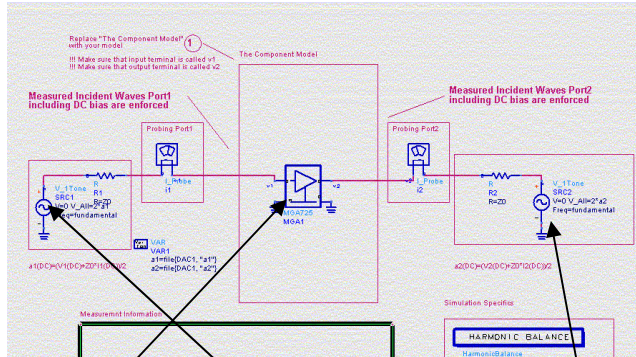


° TELEMIC / KUL

° transistor provided by David Root, Agilent Technologies - MWTC

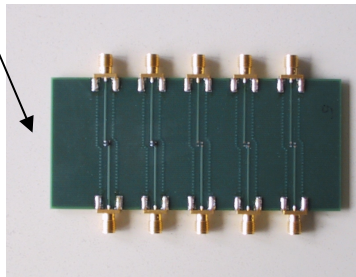
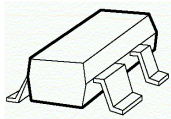
Application #2: Model Verification in CAE tool

ADS

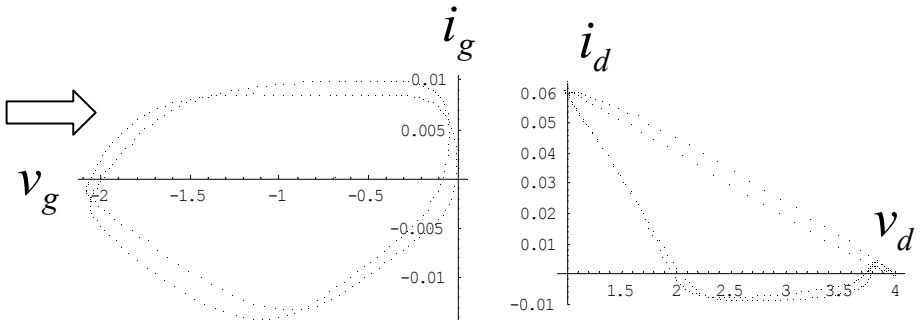
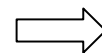
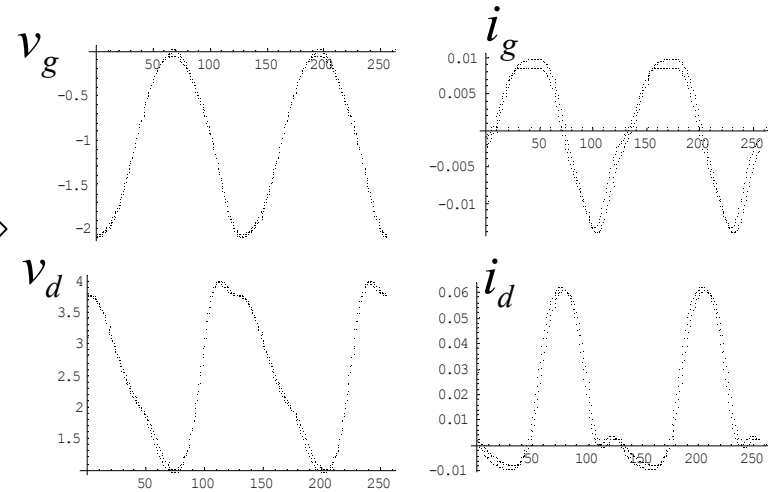
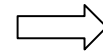
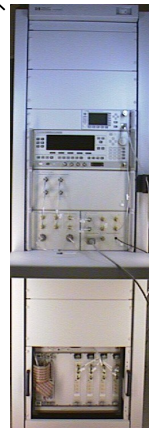


Model

Measured Incident Waves

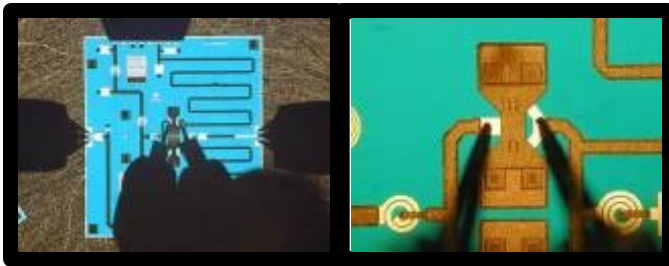


Multi-line TRL



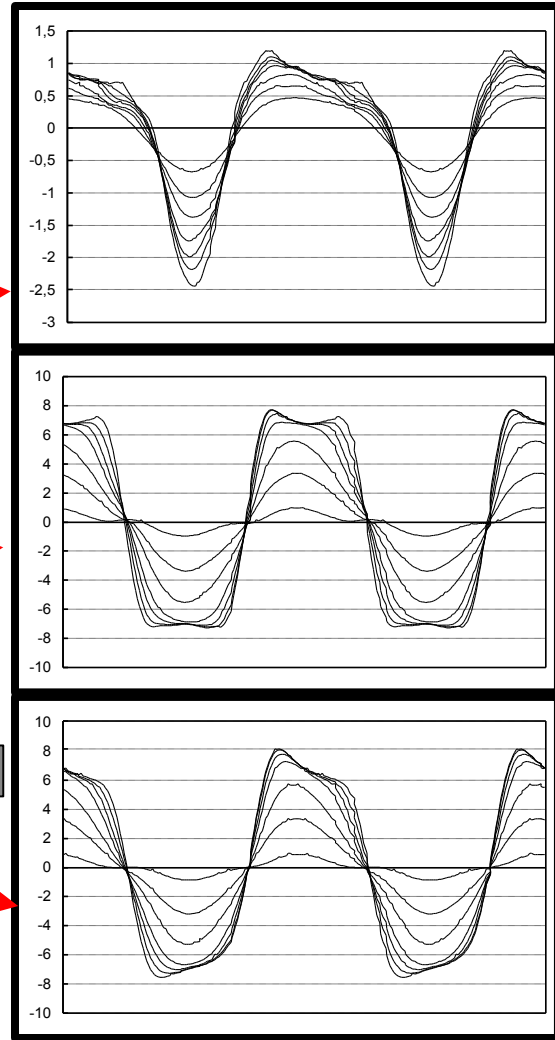
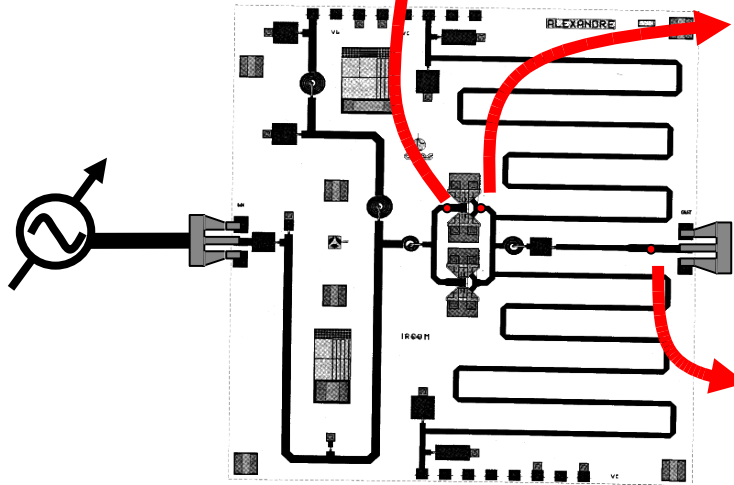
Measured and Simulated Voltages and Currents

Application #3: In-Circuit coherent and calibrated HF Signal Probing(*)



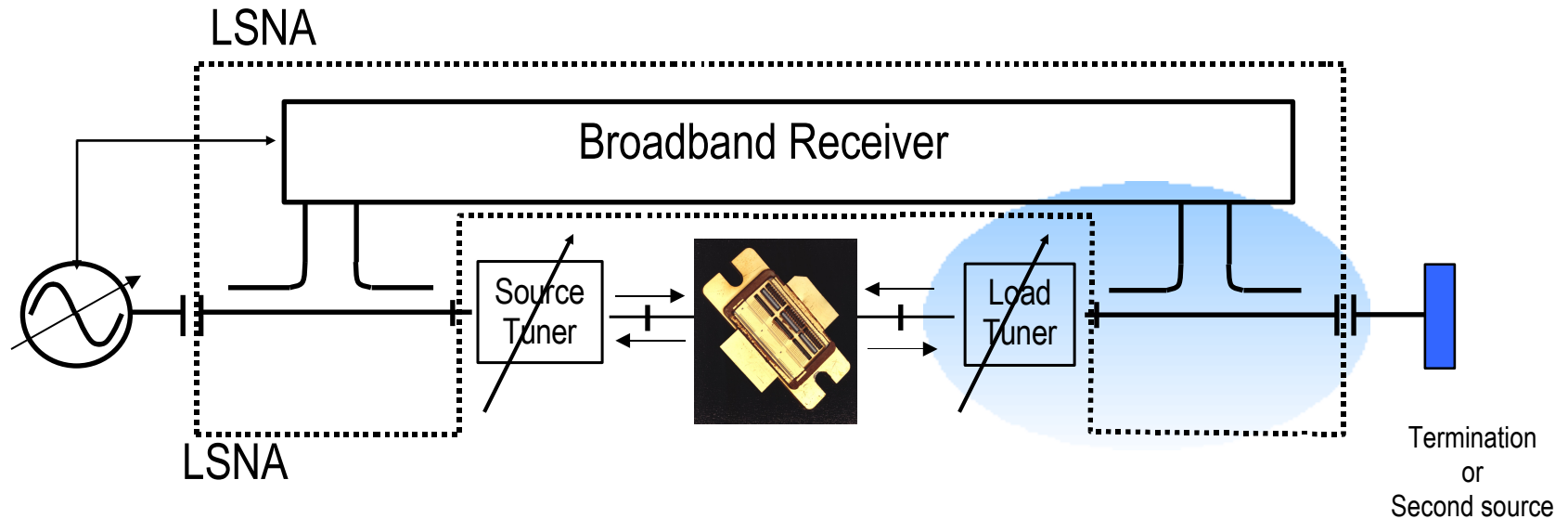
Pin

- 5
- 8
- 10
- 12
- 13
- 14
- 15



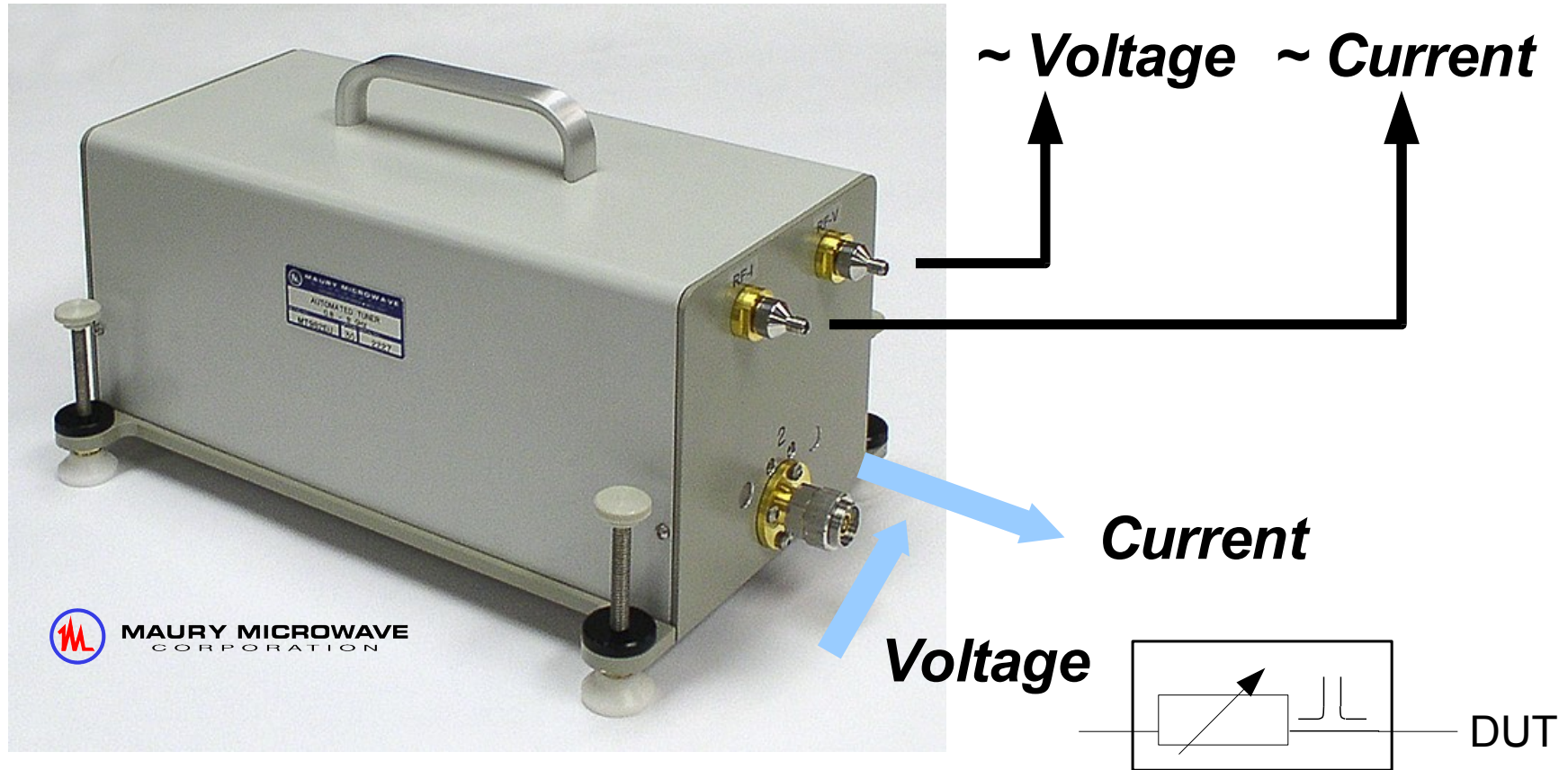
(*) With courtesy of CNES and IRCOM

LSNA and tuners: synthesizing high reflections



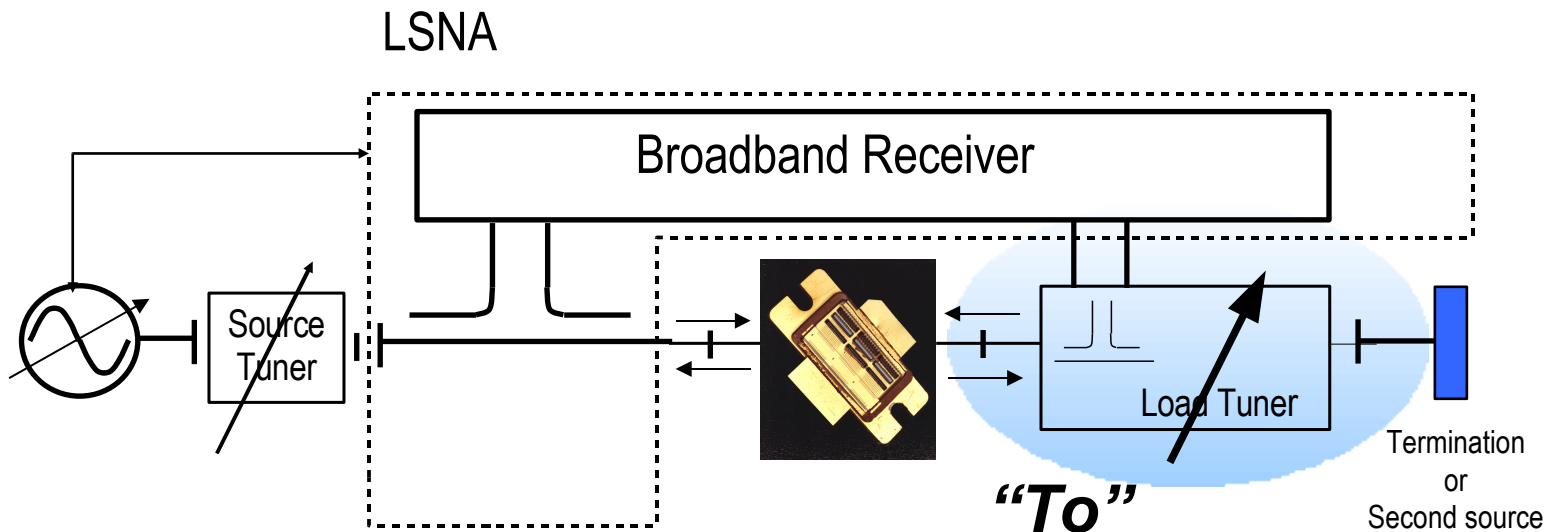
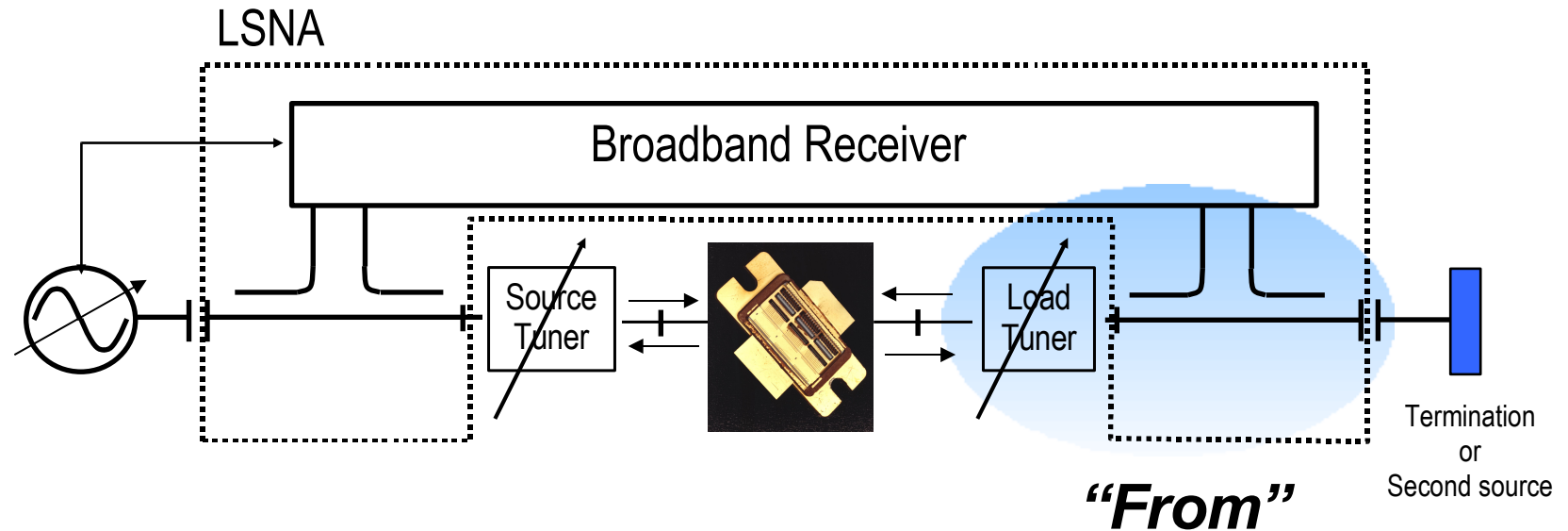
- × need for adapting de-embedding as function of tuner position
- × ill-conditioned situation in case of high reflections (typ. at harmonics)

Maury introduces the “Sensing Tuner”



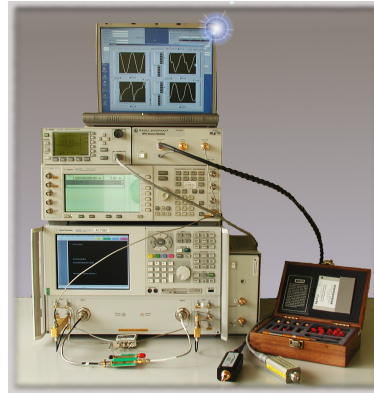
The Sensing Tuner “probes” incident / reflected waves or voltages and currents close to the device under test with a minimal insertion loss

LSNA and the Sensing Tuner





+



or



||

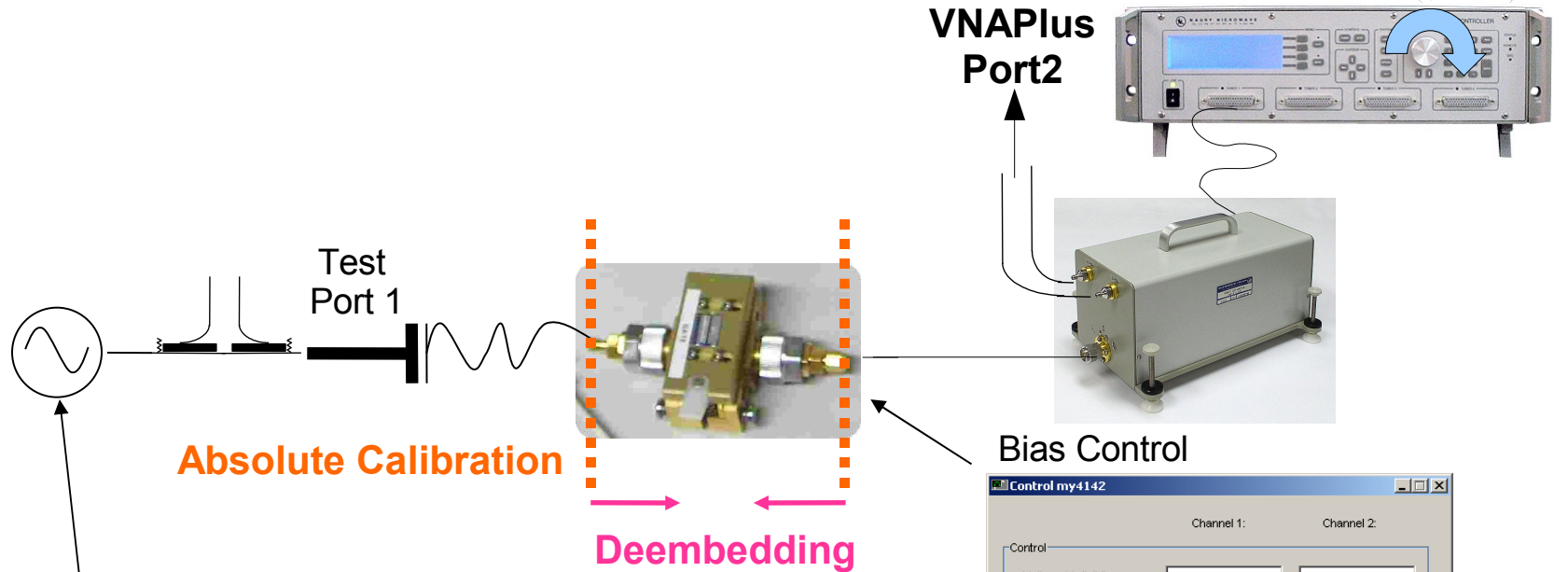


A Winning Team with many advantages
A new Frontier in the Load-Pull world

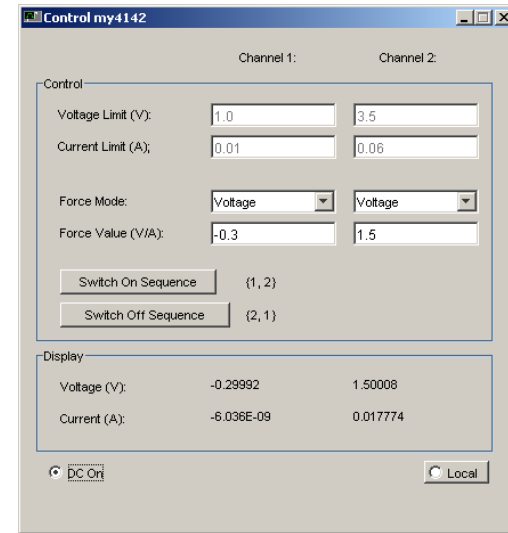
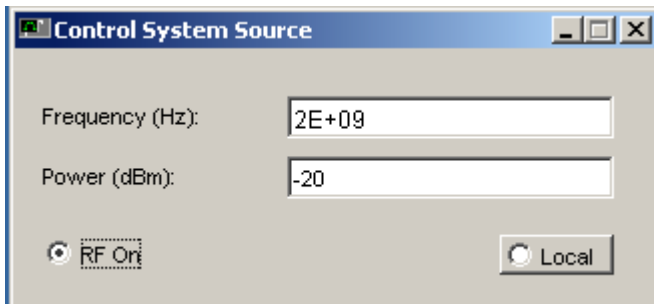
Advantages

- Ready to measure in minutes instead of hours
 - Tuners don't need to be characterized
 - Only standard LSNA calibration and possibly de-embedding is required
- Tuning resolution determined by tuner, not by its characterization
- Improved measurement accuracy
 - Measurement accuracy is set by calibration accuracy
 - No cumulation of errors by combining S-parameter blocks
- Finding optimal operating conditions in less than a minute
- Complete load-pull in a few minutes
- Harmonic load-pull and waveform engineering becomes easy

Fast Load-Pull



Synthesizer Control



$$V_{gs} = -0.3 \text{ V } V_{ds} = 1.5 \text{ V}$$

Tuning to optimal PAE

in 45 Seconds



LSNA Variables

Harmonic Freq	Modulation Freq
1f0	-4fM
2f0	-3fM
3f0	-2fM
4f0	-1fM
5f0	0

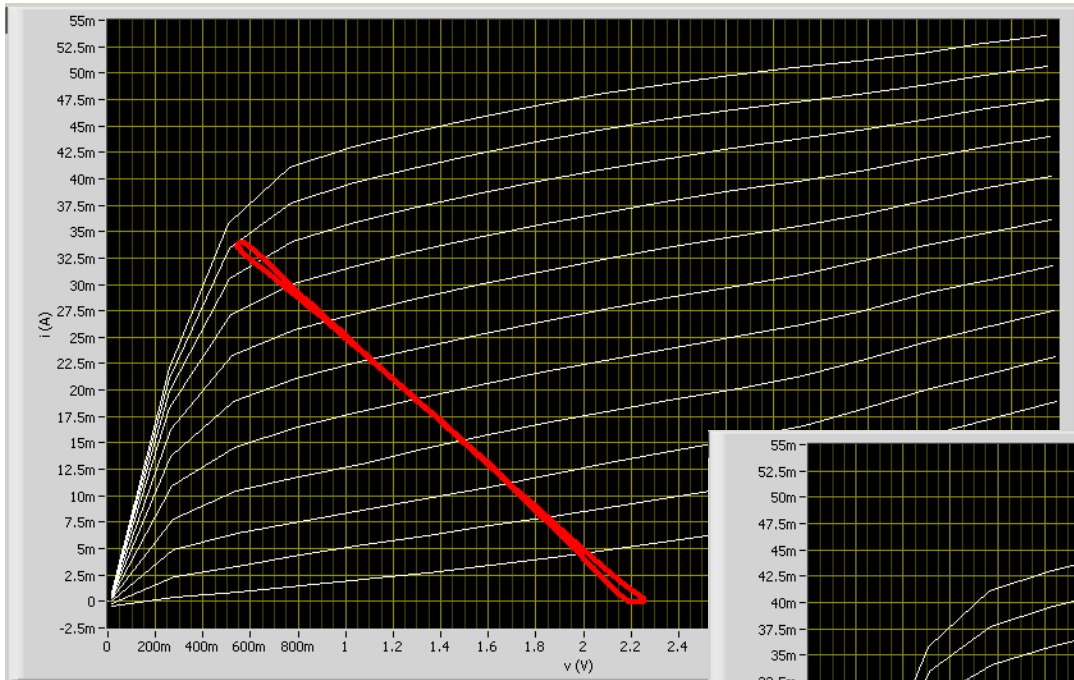
Variable	Value	Unit
Gain	-2.431E+0 + 1.276E+0 i	U
PDELIN	-13.390E+0	dBm
PDELOUT	8.986E+0	dBm
PAE	52.404E+0	U

Buttons: Add, Delete, Close

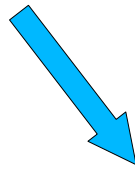
PAE: from 39 to 52%

Monitoring specifications while continuous moving tuners

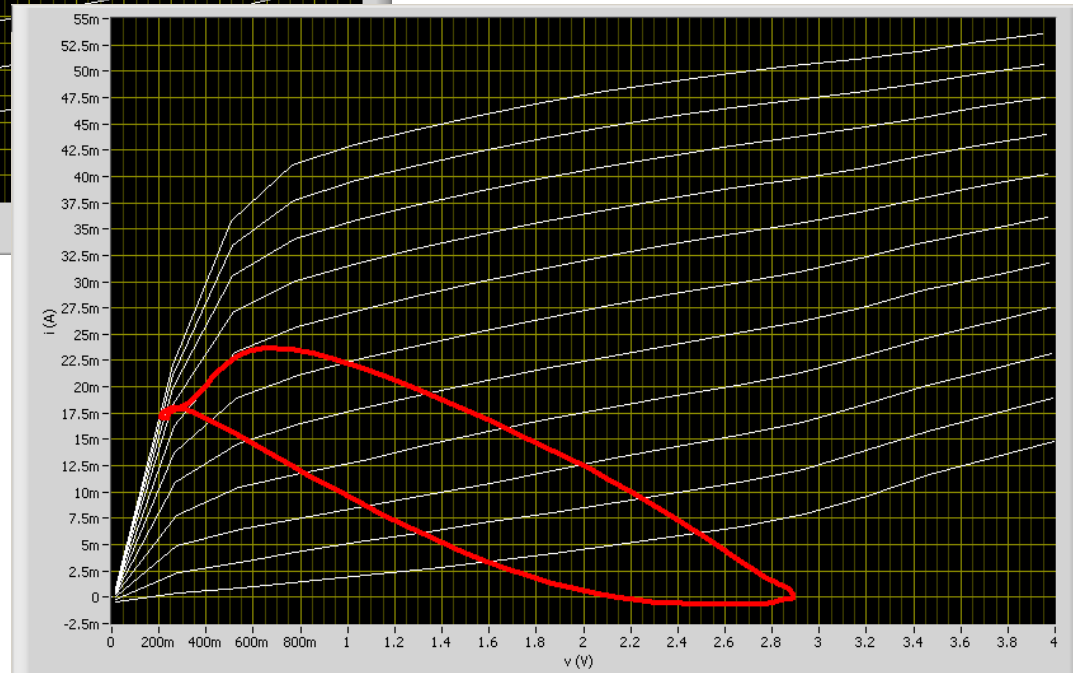
Dynamic Load-Line



PAE: 39%



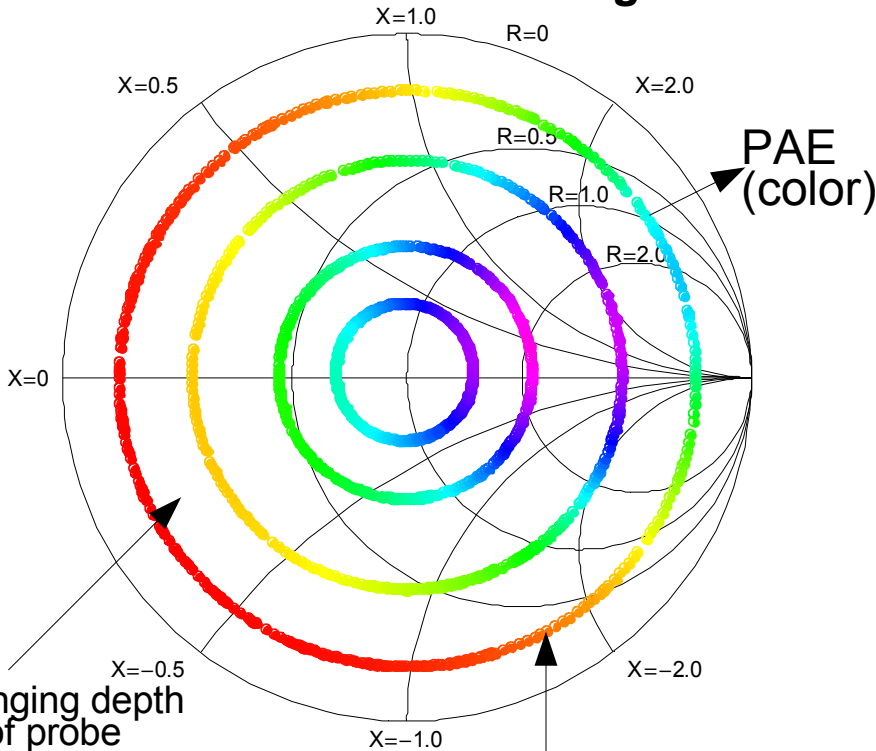
PAE: 52%



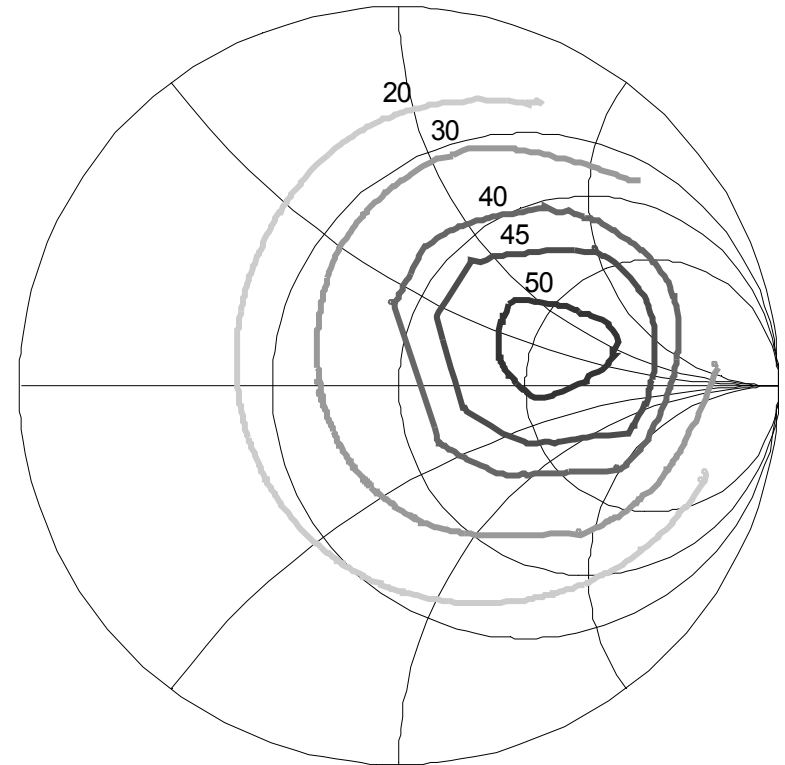
Load-Pull

in less than 3 Minutes

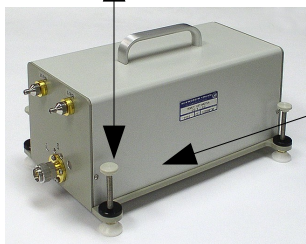
Smith Chart Coverage



PAE Contours



Changing depth of probe



Moving carriage while measuring continuously with LSNA results in a very dense reflection "circle" where the complete V/I behavior was measured

Conclusion

- Large-signal network analysis provides a uniform way to characterize the input - output behavior of nonlinear HF components under almost realistic conditions
- Incremental investment allows harmonic component characterization in time and frequency domain with a vector network analyzer in a non-50 Ohm environment
- The “Sensing Tuner” and VNAPlus: FAST, SIMPLE, ACCURATE

- For sales information www.bsw-ag.com



- For technical information www.amska.se



- info@nmdg.be
www.nmdg.be

- http://www.maurymw.com/contact_us/contact_us.htm
www.maurymw.com



A little story

